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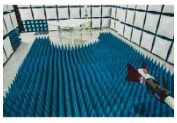

PART 22 MEASUREMENT REPORT

Applicant Name:
Apple Inc.
One Apple Park Way
Cupertino, CA 95014
United States

Date of Testing:
4/18/2024 - 6/24/2024
Test Report Issue Date:
9/9/2024
Test Site/Location:
Element Materials Technology Morgan Hill, CA, USA
Test Report Serial No.:
1C2405200018-07-R1.BCG

FCC ID:	**BCGA2995**
Applicant Name:	**Apple Inc.**

Application Type:	Certification
Model:	A2995, A2996
EUT Type:	Tablet Device
FCC Classification:	PCS Licensed Transmitter (PCB)
FCC Rule Part:	22
Test Procedure(s):	ANSI C63.26-2015, TIA-603-E-2016, KDB 971168 D01 v03r01

This equipment has been shown to be capable of compliance with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in §2.947. Test results reported herein relate only to the item(s) tested.

This revised Test Report (S/N: 1C2405200018-07-R1.BCG) supersedes and replaces the previously issued test report on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose accordingly.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

RJ Ortanez
Executive Vice President

Prepared by: WKR0000006193

Reviewed by: WKR0000005849

ACCREDITED
CERT #2041.02

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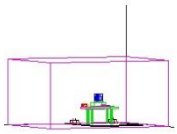
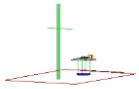


PART 22 MEASUREMENT REPORT



Mode	Bandwidth	Modulation	Tx Frequency Range [MHz]	OBW [MHz]	ERP		Emission Designator
					Max. Power [W]	Max. Power [dBm]	
WCDMA850	5 MHz	Spread Spectrum	826.4 - 846.6	4.1625	0.139	21.42	4M16F9W
Band 5	1.4 MHz	QPSK	824.7 - 848.3	1.1112	0.137	21.36	1M11G7W
		16QAM	824.7 - 848.3	1.1123	0.117	20.68	1M11D7W
		64QAM	824.7 - 848.3	1.1129	0.090	19.55	1M11D7W
		256QAM	824.7 - 848.3	1.1148	0.044	16.40	1M11D7W
	3 MHz	QPSK	825.5 - 847.5	2.7218	0.135	21.31	2M72G7W
		16QAM	825.5 - 847.5	2.7220	0.117	20.67	2M72D7W
		64QAM	825.5 - 847.5	2.7165	0.090	19.56	2M72D7W
		256QAM	825.5 - 847.5	2.7154	0.045	16.50	2M72D7W
	5 MHz	QPSK	826.5 - 846.5	4.5483	0.140	21.45	4M55G7W
		16QAM	826.5 - 846.5	4.5527	0.120	20.78	4M55D7W
		64QAM	826.5 - 846.5	4.5455	0.091	19.57	4M55D7W
		256QAM	826.5 - 846.5	4.5467	0.044	16.46	4M55D7W
	10 MHz	QPSK	829.0 - 844.0	9.0339	0.136	21.33	9M03G7W
		16QAM	829.0 - 844.0	9.0222	0.118	20.73	9M02D7W
		64QAM	829.0 - 844.0	9.0345	0.090	19.52	9M03D7W
		256QAM	829.0 - 844.0	9.0148	0.044	16.47	9M01D7W
Band 26	1.4 MHz	QPSK	824.7 - 848.3	1.1112	0.133	21.23	1M11G7W
		16QAM	824.7 - 848.3	1.1123	0.115	20.62	1M11D7W
		64QAM	824.7 - 848.3	1.1129	0.089	19.50	1M11D7W
		256QAM	824.7 - 848.3	1.1148	0.043	16.38	1M11D7W
	3 MHz	QPSK	825.5 - 847.5	2.7218	0.134	21.28	2M72G7W
		16QAM	825.5 - 847.5	2.7220	0.117	20.67	2M72D7W
		64QAM	825.5 - 847.5	2.7165	0.092	19.63	2M72D7W
		256QAM	825.5 - 847.5	2.7154	0.045	16.52	2M72D7W
	5 MHz	QPSK	826.5 - 846.5	4.5483	0.140	21.45	4M55G7W
		16QAM	826.5 - 846.5	4.5527	0.116	20.64	4M55D7W
		64QAM	826.5 - 846.5	4.5455	0.093	19.69	4M55D7W
		256QAM	826.5 - 846.5	4.5467	0.044	16.46	4M55D7W
	10 MHz	QPSK	829.0 - 844.0	9.0339	0.134	21.27	9M03G7W
		16QAM	829.0 - 844.0	9.0222	0.116	20.65	9M02D7W
		64QAM	829.0 - 844.0	9.0345	0.090	19.53	9M03D7W
		256QAM	829.0 - 844.0	9.0148	0.045	16.58	9M01D7W
ULCA Band 5	10 + 10 MHz	QPSK	829.0 - 844.0	18.9120	0.138	21.40	18M9G7W
		16QAM	829.0 - 844.0	18.9030	0.070	18.48	18M9D7W
		64QAM	829.0 - 844.0	18.8730	0.069	18.36	18M9D7W
		256QAM	829.0 - 844.0	18.8530	0.044	16.44	18M9D7W

EUT Overview

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Mode	Bandwidth	Modulation	Tx Frequency Range [MHz]	OBW [MHz]	ERP		Emission Designator
					Max. Power [W]	Max. Power [dBm]	
NR Band n5	5 MHz	π/2 BPSK	826.5 - 846.5	4.4860	0.140	21.45	4M49G7W
		QPSK	826.5 - 846.5	4.4832	0.137	21.37	4M48G7W
		16QAM	826.5 - 846.5	4.4908	0.111	20.47	4M49D7W
		64QAM	826.5 - 846.5	4.4557	0.088	19.45	4M46D7W
		256QAM	826.5 - 846.5	4.4774	0.044	16.44	4M48D7W
	10 MHz	π/2 BPSK	829.0 - 844.0	8.9426	0.139	21.42	8M94G7W
		QPSK	829.0 - 844.0	9.2572	0.140	21.45	9M26G7W
		16QAM	829.0 - 844.0	9.2747	0.112	20.48	9M27D7W
		64QAM	829.0 - 844.0	9.2875	0.089	19.48	9M29D7W
		256QAM	829.0 - 844.0	9.2625	0.045	16.58	9M26D7W
	15 MHz	π/2 BPSK	831.5 - 841.5	13.4410	0.140	21.45	13M4G7W
		QPSK	831.5 - 841.5	14.1263	0.137	21.37	14M1G7W
		16QAM	831.5 - 841.5	14.1173	0.107	20.29	14M1D7W
		64QAM	831.5 - 841.5	14.0457	0.087	19.40	14M0D7W
		256QAM	831.5 - 841.5	14.1354	0.045	16.55	14M1D7W
	20 MHz	π/2 BPSK	834.0 - 839.0	17.8903	0.140	21.45	17M9G7W
		QPSK	834.0 - 839.0	19.0320	0.140	21.45	19M0G7W
		16QAM	834.0 - 839.0	18.9444	0.111	20.46	18M9D7W
		64QAM	834.0 - 839.0	18.8717	0.088	19.44	18M9D7W
		256QAM	834.0 - 839.0	18.9784	0.045	16.49	19M0D7W
NR Band n26	5 MHz	π/2 BPSK	826.5 - 846.5	4.4860	0.138	21.39	4M49G7W
		QPSK	826.5 - 846.5	4.4832	0.140	21.45	4M48G7W
		16QAM	826.5 - 846.5	4.4908	0.109	20.37	4M49D7W
		64QAM	826.5 - 846.5	4.4557	0.088	19.45	4M46D7W
		256QAM	826.5 - 846.5	4.4774	0.044	16.44	4M48D7W
	10 MHz	π/2 BPSK	829.0 - 844.0	8.9426	0.140	21.45	8M94G7W
		QPSK	829.0 - 844.0	9.2572	0.140	21.45	9M26G7W
		16QAM	829.0 - 844.0	9.2747	0.110	20.42	9M27D7W
		64QAM	829.0 - 844.0	9.2875	0.089	19.49	9M29D7W
		256QAM	829.0 - 844.0	9.2625	0.045	16.53	9M26D7W
	15 MHz	π/2 BPSK	831.5 - 841.5	13.4410	0.139	21.44	13M4G7W
		QPSK	831.5 - 841.5	14.1263	0.140	21.45	14M1G7W
		16QAM	831.5 - 841.5	14.1173	0.111	20.44	14M1D7W
		64QAM	831.5 - 841.5	14.0457	0.085	19.28	14M0D7W
		256QAM	831.5 - 841.5	14.1354	0.045	16.53	14M1D7W
	20 MHz	π/2 BPSK	834.0 - 839.0	17.8903	0.139	21.44	17M9G7W
		QPSK	834.0 - 839.0	19.0320	0.140	21.45	19M0G7W
		16QAM	834.0 - 839.0	18.9444	0.110	20.40	18M9D7W
		64QAM	834.0 - 839.0	18.8717	0.087	19.41	18M9D7W
		256QAM	834.0 - 839.0	18.9784	0.045	16.51	19M0D7W

EUT Overview

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1.0 INTRODUCTION

1.1 Scope

Measurement and determination of electromagnetic emissions (EMC) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Innovation, Science and Economic Development Canada.

1.2 Element Materials Technology Test Location

These measurement tests were conducted at the Element Materials Technology facility located at 18855 Adams Court, Morgan Hill, CA 95037. The measurement facility is compliant with the test site requirements specified in ANSI C63.4-2014 and KDB 414788 D01 v01r01.

1.3 Test Facility / Accreditations

Measurements were performed at Element Materials Technology.

- Element Materials Technology is an ISO 17025-2017 accredited test facility under the American Association for Laboratory Accreditation (A2LA) with Certificate number 2041.02 for Specific Absorption Rate (SAR), Hearing Aid Compatibility (HAC) testing, where applicable, and Electromagnetic Compatibility (EMC) testing for FCC and Innovation, Science, and Economic Development Canada rules.

- Element Materials Technology TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC 17065-2012 by A2LA (Certificate number 2041.03) in all scopes of FCC Rules and ISED Standards (RSS).

- Element Materials Technology facility is a registered (22831) test laboratory with the site description on file with ISED.

- Element Washington DC LLC is a Recognized U.S. Certification Assessment Body (CAB # US0110) for ISED Canada as designated by NIST under the U.S. and Canada Mutal Recognition Agreements (MRAs).

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2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Apple Tablet Device FCC ID: BCGA2995**. The test data contained in this report pertains only to the emissions due to the EUT's licensed transmitters that operate under the provisions of Part 22.

Test Device Serial No.: WH6226Y7R5, D74GQ0GVJR, DVXJDXL1QN, H9HH5F000230000CFX

2.2 Device Capabilities

This device contains the following capabilities:

850/1700/1900 WCDMA/HSPA, Multi-band LTE, 5G NR (FR1), 802.11b/g/n/ax WLAN, 802.11a/n/ac/ax UNII, 802.11a/ax WIFI 6E, 802.15.4, Bluetooth (1x, EDR, LE1M, LE2M, HDR4, HDR8), NB UNII (1x, HDR4, HDR8), WPT

This device supports BT Beamforming

This device supports simultaneous transmission operations, which allows for multiple transmitters to transmit simultaneously on the same antenna. The table below shows all configurations possible.

Antenna	Simultaneous Tx Config	Bluetooth 2.4GHz	Thread	NB UNII	WLAN	WIFI 5GHz	WIFI 6GHz	LTE / FR1 NR		
		BDR, EDR, HDR4/8, LE1/2M	802.15.4	BDR, HDR4/8	802.11 b/g/n/ax	802.11 a/n/ac/ax	802.11 a/ax	LB	MB/HB	Ultra High Band
1a	Config 1	✓	×	×	×	×	×	×	×	✓
1a	Config 2	×	×	×	✓	×	×	×	×	✓
1a	Config 3	×	✓	×	×	×	×	×	×	✓
1b	Config 4	×	×	✓	×	×	×	×	✓	×
1b	Config 5	×	×	×	×	✓	×	×	✓	×
1b	Config 6	×	×	×	×	×	✓	×	✓	×
3a	Config 7	×	×	×	✓	×	×	×	×	✓
3a	Config 8	✓	×	×	×	×	×	×	×	✓
3a	Config 9	×	✓	×	×	×	×	×	×	✓
3b	Config 10	×	×	✓	×	×	×	×	✓	×
3b	Config 11	×	×	×	×	✓	×	×	✓	×
3b	Config 12	×	×	×	×	×	✓	×	✓	×
4	Config 13	✓	×	×	×	×	×	✓	×	×
4	Config 14	✓	×	×	×	×	×	×	✓	×
4	Config 15	✓	×	×	×	×	×	×	×	✓
4	Config 16	×	✓	×	×	×	×	✓	×	×
4	Config 17	×	✓	×	×	×	×	×	✓	×
4	Config 18	×	✓	×	×	×	×	×	×	✓

Table 2-1. Simultaneous Transmission Configurations

✓ = Support; × = Not Support

Note:

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All the above simultaneous transmission configurations have been tested and the worst-case configuration was found to be Config 14 and reported in RF Bluetooth, RF FCC Part 27b test reports.

Specific 2.4GHz Wi-Fi antenna that can only transmit simultaneously with 2.4GHz Bluetooth antenna is listed in the SAR test report. For BT (2.4GHz), in both connected and disconnected modes, and Wi-Fi (2.4GHz) - Wi-Fi max power will not exceed minimum of (13.5dBm, SAR max cap, Reg max cap) power. Bluetooth can simultaneously transmit with IEEE 802.11a/n/ac/ax 5/6 GHz on separate antenna.

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2.3 Antenna Description

The following antenna gains provided by the manufacturer were used for testing.

Band	Antenna Gain [dBi]	
	Antenna 4	Antenna 2
WCDMA 850	-1.8	-2.4
LTE Band 26/5		
NR Band n26/5		

Table 2-2. Highest Antenna Gain

2.4 Test Support Equipment

1	Apple MacBook Pro	Model:	A2141	S/N:	C02H604EQ05D
	w/AC/DC Adapter	Model:	A2166	S/N:	C4H042705ZNPM0WA6
2	Apple USB-C Cable	Model:	Spartan	S/N:	GXK1336018XKTR024
3	USB-C Cable	Model:	A246C	S/N:	DWH80115BK826GV19
	w/ AC Adapter	Model:	A2305	S/N:	C4H95160004PF4F4V
4	Apple Pencil	Model:	A2538	S/N:	KJ26TCFXJW
5	DC Power Supply	Model:	KPS3010D	S/N:	N/A

Table 2-3. Test Support Equipment

2.5 Test Configuration

The EUT was tested per the guidance of ANSI C63.26 2015, TIA-603-E-2016 and KDB 971168 D01 v03r01. See Section 7.0 of this test report for a description of the radiated and antenna port conducted emissions tests.

For emissions from 1GHz – 18GHz, low, mid, and high channels were tested with highest power and worst case configuration. The emissions below 1GHz were tested with the highest transmitting power and the worst case channel.

The EUT was manipulated through three orthogonal planes of X-orientation (flatbed), Y-orientation (landscape), and Z-orientation (portrait) during the testing. Only the worst case emissions were reported in this test report.

2.6 Software and Firmware

The test was conducted with firmware version 22A312 installed on the EUT.

2.7 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

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3.0 DESCRIPTION OF TESTS

3.1 Measurement Procedure

The measurement procedures described in the documents titled "American National Standard for Compliance Testing of Transmitters Used in Licensed Radio Services" (ANSI C63.26-2015 and TIA-603-E-2016) and "Procedures for Compliance Measurement of the Fundamental Emission Power of Licensed Wideband (> 1 MHz) Digital Transmission Systems" (KDB 971168 D01 v03r01) were used in the measurement of the EUT.

Deviation from Measurement Procedure……..……..None

3.2 Radiated Spurious Emissions

The radiated test facilities consisted of an indoor 3 meter semi-anechoic chamber used for final measurements and exploratory measurements, when necessary. The measurement area is contained within the semi-anechoic chamber which is shielded from any ambient interference. The test site inside the chamber is a 6m x 5.2m elliptical, obstruction-free area in accordance with Figure 5.7 of Clause 5 in ANSI C63.4-2014. Absorbers are arranged on the floor between the turn table and the antenna mast in such a way so as to maximize the reduction of reflections for measurements above 1GHz. For measurements below 1GHz, the absorbers are removed. A raised turntable is used for radiated measurement. The turn table is a continuously rotatable, remote-controlled, metallic turntable and 2 meters (6.56 ft.) in diameter. The turn table is flush with the raised floor of the chamber in order to maintain its function as a ground plane. An 80cm tall test table made of Styrodur is placed on top of the turn table. A Styrodur pedestal is placed on top of the test table to bring the total table height to 1.5m.

The equipment under test was transmitting while connected to its integral antenna and is placed on a turntable 3 meters from the receive antenna. The receive antenna height is adjusted between 1 and 4 meter height, the turntable is rotated through 360 degrees, and the EUT is manipulated through all orthogonal planes representative of its typical use to achieve the highest reading on the receive spectrum analyzer.

For radiated spurious emissions measurements and calculations, conversion method is used per the formulas in KDB 971168 Section 5.8.4. Field Strength (EIRP) is calculated using the following formulas:

$$E_{[dB\mu V/m]} = \text{Measured amplitude level}_{[dBm]} + 107 + \text{Cable Loss}_{[dB]} + \text{Antenna Factor}_{[dB/m]}$$

And

$$EIRP_{[dBm]} = E_{[dB\mu V/m]} + 20\log D - 104.8;$$ where D is the measurement distance in meters.

All radiated measurements are performed in a chamber that meets the site requirements per ANSI C63.4-2014.

Per KDB 414788 D01 v01r01, radiated emission test sites other than open-field test sites (e.g., shielded anechoic chambers), may be employed for emission measurements below 30MHz if characterized so that the measurements correspond to those obtained at an open-field test site. To determine test site equivalency, a reference sample transmitting at 149kHz was measured on an open field test site (asphalt with no ground plane) and then measured in the 3m semi-anechoic chamber. A calibrated 60cm loop antenna was used while the reference device was rotated through the X, Y and Z axis in order to capture the worst case level. A maximum deviation of 2.77dB at 149kHz was measured when comparing the 3 meter semi-anechoic chamber to the open field site.

Radiated spurious emission levels are investigated with the receive antenna horizontally and vertically polarized per ANSI C63.26-2015 and TIA-603-E-2016.

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4.0 MEASUREMENT UNCERTAINTY

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI C63.23-2012.All measurement uncertainty values are shown with a coverage factor of k = 2 to indicate a 95% level of confidence. The measurement uncertainty shown below meets or exceeds the U_{CISPR} measurement uncertainty values specified in CISPR 16-4-2 and, thus, can be compared directly to specified limits to determine compliance.

Contribution	Expanded Uncertainty (±dB)
Conducted Bench Top Measurements	2.07
Radiated Disturbance (<30MHz)	4.12
Radiated Disturbance (30MHz-1GHz)	4.85
Radiated Disturbance (1-18GHz)	5.08
Radiated Disturbance (>18GHz)	5.22

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5.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST). Measurements antennas used during testing were calibrated in accordance to the requirements of ANSI C63.5-2017.

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
ATM	180-442A-KF	20dB Nominal Gain Horn Antenna	3/14/2024	Annual	3/14/2025	T058701-01
ESPEC	SU-241	Tabletop Temperature Chamber	11/17/2023	Annual	11/17/2024	92009574
ETS-Lindgren	3117	Double Ridged Guide Antenna (1-18 GHz)	4/9/2024	Annual	4/9/2025	00218555
Fairview Microwave	FMCA1975-36	30MHz-40GHz Conducted Cable *	6/10/2024	Annual	6/10/2025	-
Fairview Microwave	M2CP1122-10	30MHz-40GHz Conducted Coupler *	6/10/2024	Annual	6/10/2025	1946
Fairview Microwave/MCL	1975-36/BW-K10-2	30MHz-40GHz Conducted Cable/Attenuator *	6/10/2024	Annual	6/10/2025	-
Keysight Technology	N9040B	UXA Signal Analyzer	5/28/2024	Annual	5/28/2025	MY57212015
Rohde & Schwarz	TS-PR18	Pre-Amplifier (1GHz - 18GHz)	8/15/2023	Annual	8/15/2024	101639
Rohde & Schwarz	TS-PR18	Pre-Amplifier (1GHz - 18GHz)	8/14/2024	Annual	8/15/2025	101648
Rohde & Schwarz	FSV40	Signal Analyzer (10Hz-40GHz)	5/29/2024	Annual	5/29/2025	101619
Rohde & Schwarz	ESW44	EMI Test Receiver	5/1/2024	Annual	5/1/2025	101867
Rohde & Schwarz	FSW67	Signal and Spectrum Analyzer (2Hz-67GHz)	7/5/2024	Annual	7/5/2025	101366
Rohde & Schwarz	TS-PR8	Pre-Amplifier (30MHz - 8GHz)	7/3/2024	Annual	7/3/2025	102356
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	11/30/2023	Annual	11/30/2024	161616
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	12/27/2023	Annual	12/27/2024	164715
Rohde & Schwarz	TS-PR1840	Pre-Amplifier (18GHz - 40GHz)	6/10/2024	Annual	6/10/2025	100057
Rohde & Schwarz	HFH2-Z2	Loop Antenna	6/21/2024	Annual	6/21/2025	100519
Rohde & Schwarz	ENV216	Two-Line V-Network	4/24/2024	Annual	4/24/2025	101364
Schwarzbeck	VULB 9162	Bilog Antenna (30MHz - 6GHz)	4/29/2024	Annual	4/29/2025	00304

Table 5-1. Test Equipment

Notes:

1. For equipment listed above that has a calibration date or calibration due date that falls within the test date range, care was taken to ensure that this equipment was used after the calibration date and before the calibration due date.
2. * denotes passive equipment that have been internally verified/calibrated.

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6.0 SAMPLE CALCULATIONS

Emission Designator

WCDMA Emission Designator

Emission Designator = 4M16F9W
WCDMA BW = 4.16 MHz
F = Frequency Modulation
9 = Composite Digital Info
W = Combination (Audio/Data)

π/2 BPSK / QPSK Modulation

Emission Designator = 8M62G7W
BW = 8.62 MHz
G = Phase Modulation
7 = Quantized/Digital Info
W = Combination of Any

QAM Modulation

Emission Designator = 8M45D7W
BW = 8.45 MHz
D = Amplitude/Angle Modulated
7 = Quantized/Digital Info
W = Combination of Any

Spurious Radiated Emission

Example: Spurious emission at 3700.40 MHz

The receive spectrum analyzer reading at 3 meters with the EUT on the turntable was –81.0 dBm. The gain of the substituted antenna is 8.1 dBi. The signal generator connected to the substituted antenna terminals is adjusted to produce a reading of –81.0 dBm on the spectrum analyzer. The loss of the cable between the signal generator and the terminals of the substituted antenna is 2.0 dB at 3700.40 MHz. So 6.1 dB is added to the signal generator reading of –30.9 dBm yielding –24.80 dBm. The fundamental EIRP was 25.50 dBm so this harmonic was 25.50 dBm – (-24.80) = 50.3 dBc.

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7.0 TEST RESULTS

7.1 Summary

Company Name: Apple Inc.

FCC ID: BCGA2995

FCC Classification: PCS Licensed Transmitter (PCB)

Mode(s): WCDMA/LTE/NR

Test Condition	Test Description	FCC Part Section(s)	Test Limit	Test Result	Reference
CONDUCTED	Occupied Bandwidth	2.1049	N/A	**N/A**	Section 7.2
	Conducted Band Edge / Spurious Emissions	2.1051, 22.917(a)	-13 dBm at Band Edge and for all out-of-band emissions	**PASS**	Sections 7.3, 7.4
	Transmitter Conducted Output Power	2.1046	N/A	**N/A**	See RF Exposure Report
	Effective Radiated Power / Equivalent Isotropic Radiated Power	22.913(a)(5)	< 7 Watts max. ERP	**PASS**	Section 7.5
	Frequency Stability	2.1055, 22.355	±2.5 ppm	**PASS**	Section 7.7
RADIATED	Radiated Spurious Emissions	2.1053, 22.917(a)	-13 dBm for all out-of-band emissions	**PASS**	Section 7.6

Table 7-1. Summary of Test Results

Notes:

1. All modes of operation and data rates were investigated. The test results shown in the following sections represent the worst case emissions.
2. The analyzer plots were all taken with a correction table loaded into the analyzer. The correction table was used to account for the losses of the cables, directional couplers, and attenuators used as part of the system to maintain a link between the call box and the EUT at all frequencies of interest.
3. All antenna port conducted emissions testing was performed on a test bench with the antenna port of the EUT connected to the spectrum analyzer through calibrated cables, attenuators, and couplers.
4. All conducted emissions measurements are performed with automated test software to capture the corresponding plots necessary to show compliance. The measurement software utilized is Element EMC Software Tool v1.1

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7.2 Occupied Bandwidth

§2.1049

Test Overview

The occupied bandwidth, that is the frequency bandwidth such that, below its lower and above its upper frequency limits, the mean powers radiated are each equal to 0.5 percent of the total mean power radiated by a given emission shall be measured. All modes of operation were investigated and the worst case configuration results are reported in this section. All ports were tested and only the worst case data were reported.

Test Procedure Used

KDB 971168 D01 v03r01 – Section 4.2

Test Settings

1. The signal analyzer's automatic bandwidth measurement capability was used to perform the 99% occupied bandwidth and the 26dB bandwidth. The bandwidth measurement was not influenced by any intermediate power nulls in the fundamental emission.
2. RBW = 1 – 5% of the expected OBW
3. VBW ≥ 3 x RBW
4. Detector = Peak
5. Trace mode = max hold
6. Sweep = auto couple
7. The trace was allowed to stabilize
8. If necessary, steps 2 – 7 were repeated after changing the RBW such that it would be within 1 – 5% of the 99% occupied bandwidth observed in Step 7

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Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

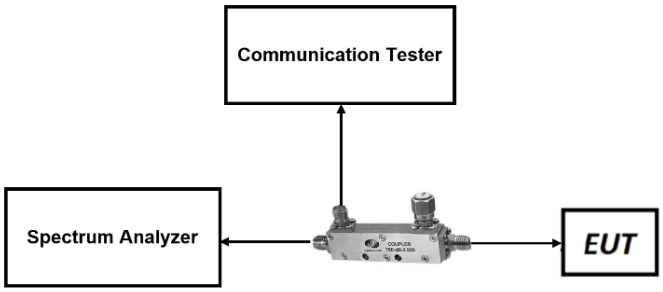

Figure 7-1. LTE Test Instrument & Measurement Setup

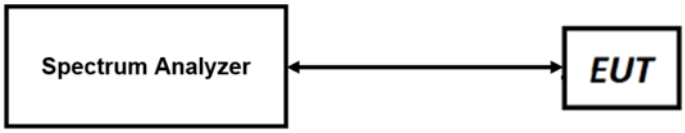

Figure 7-2. FR1 Test Instrument & Measurement Setup

Test Notes

None.

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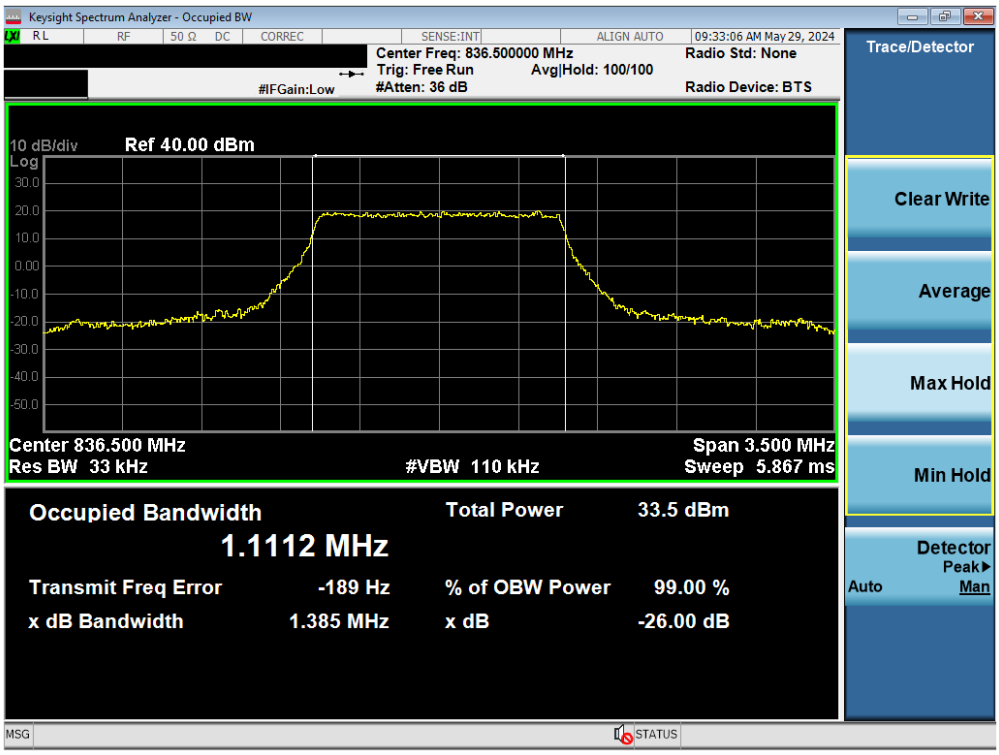
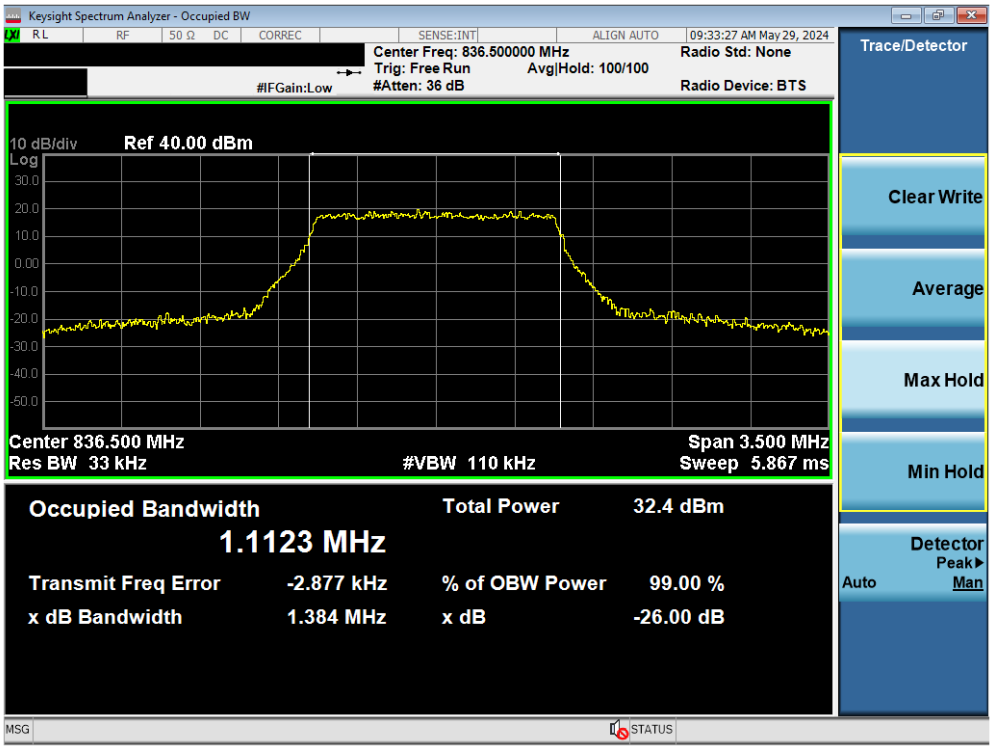
LTE Band 26/5



Plot 7-1. Occupied Bandwidth Plot (LTE Band 26/5 - 1.4MHz QPSK - Full RB Configuration)



Plot 7-2. Occupied Bandwidth Plot (LTE Band 26/5 - 1.4MHz 16-QAM - Full RB Configuration)

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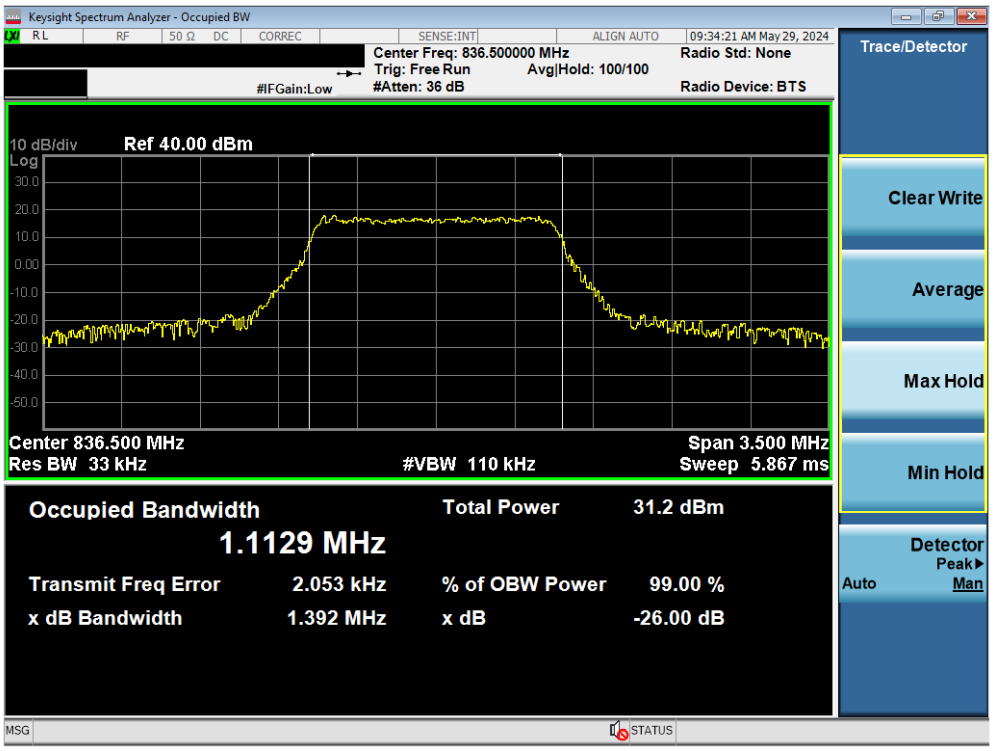
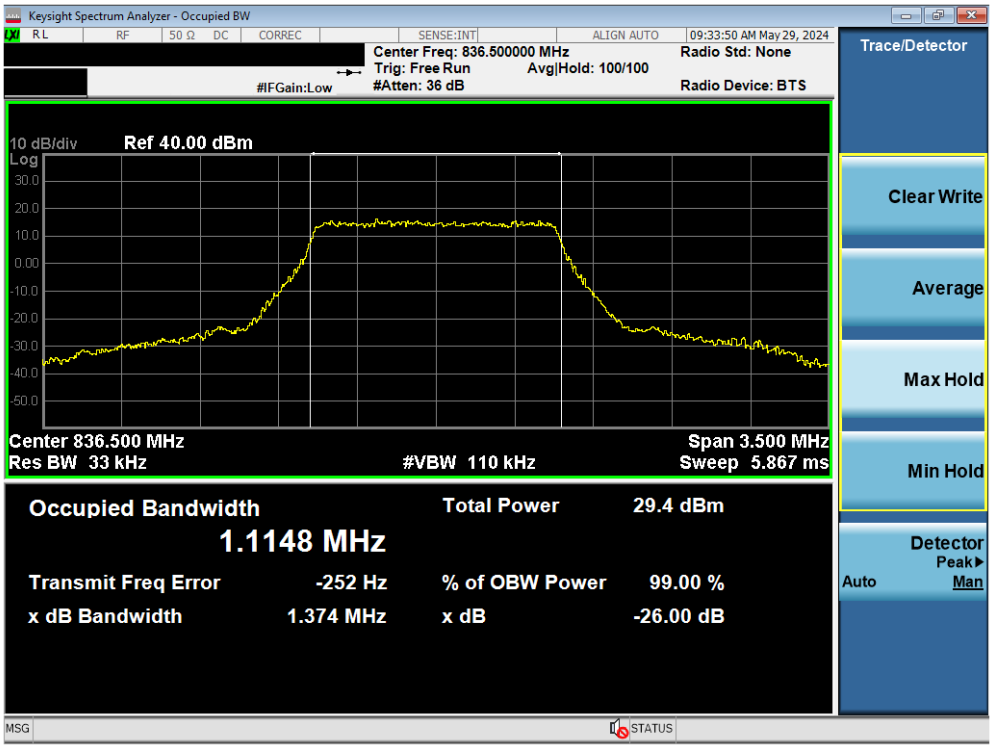


Plot 7-3. Occupied Bandwidth Plot (LTE Band 26/5 - 1.4MHz 64-QAM - Full RB Configuration)



Plot 7-4. Occupied Bandwidth Plot (LTE Band 26/5 - 1.4MHz 256-QAM - Full RB Configuration)

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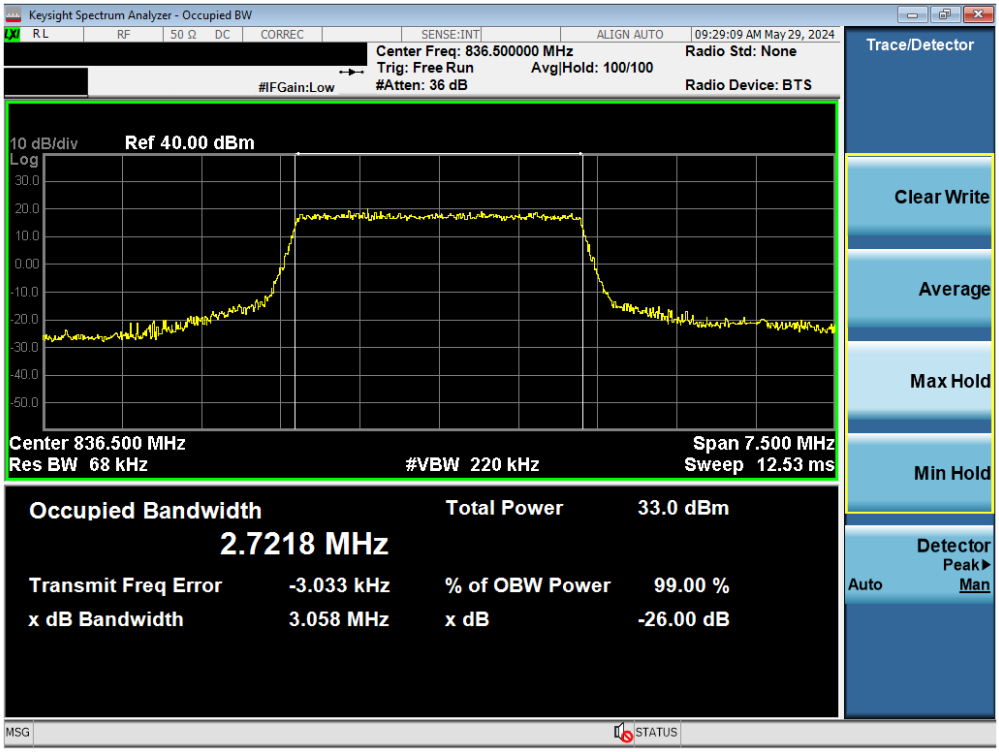
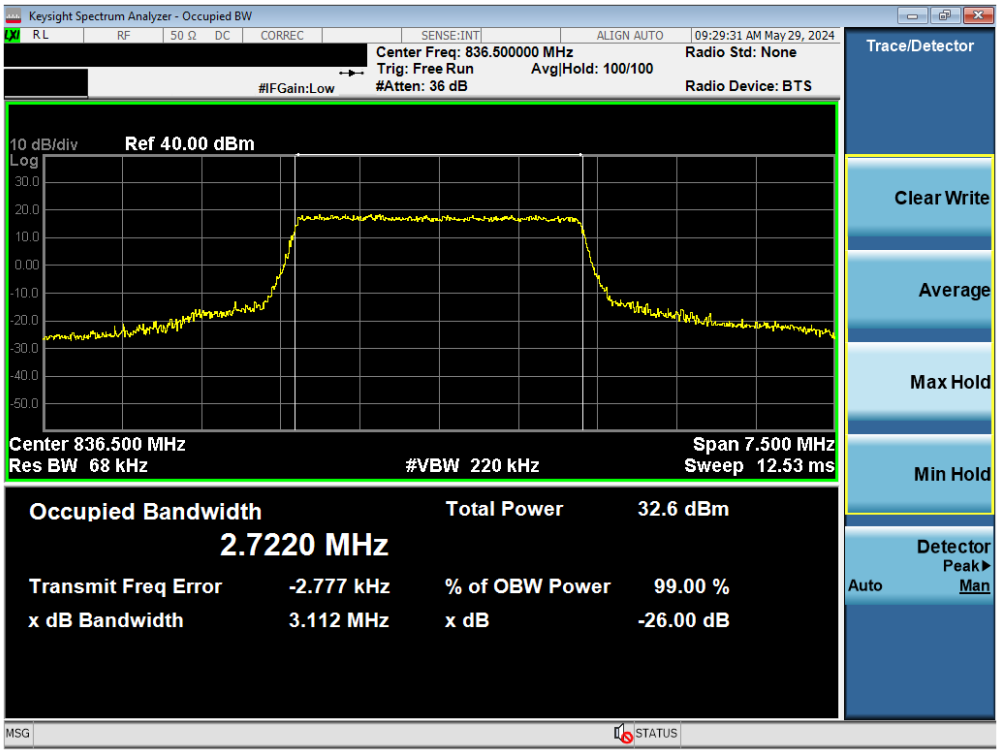


Plot 7-5. Occupied Bandwidth Plot (LTE Band 26/5 - 3MHz QPSK - Full RB Configuration)



Plot 7-6. Occupied Bandwidth Plot (LTE Band 26/5 - 3MHz 16-QAM - Full RB Configuration)

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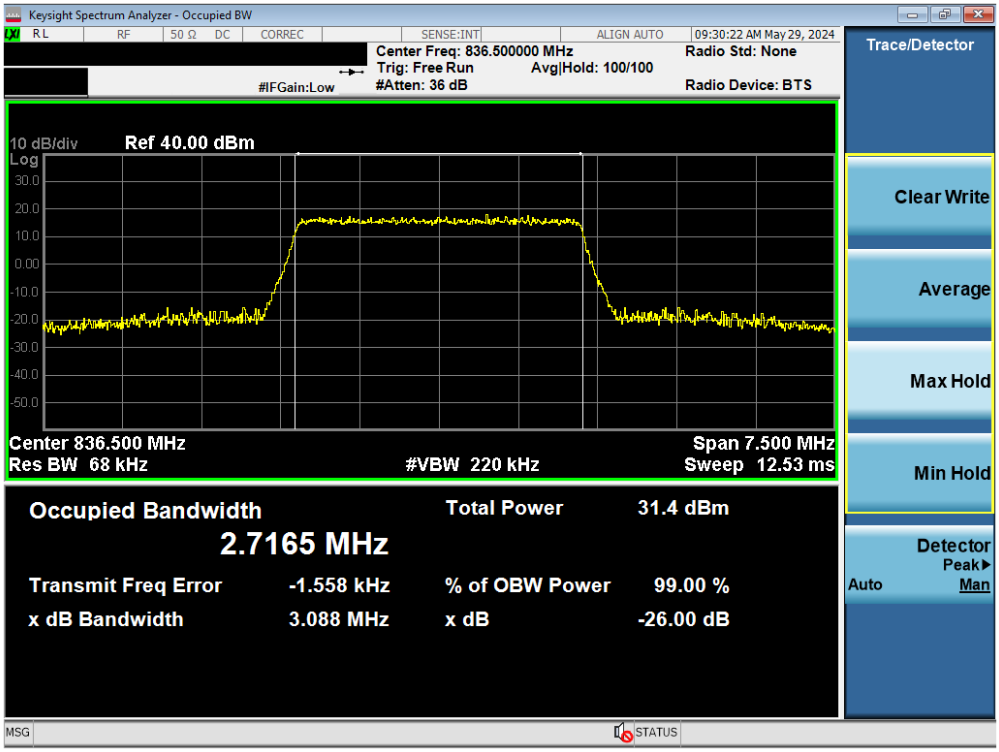

Plot 7-7. Occupied Bandwidth Plot (LTE Band 26/5 - 3MHz 64-QAM - Full RB Configuration)

Plot 7-8. Occupied Bandwidth Plot (LTE Band 26/5 - 3MHz 256-QAM - Full RB Configuration)

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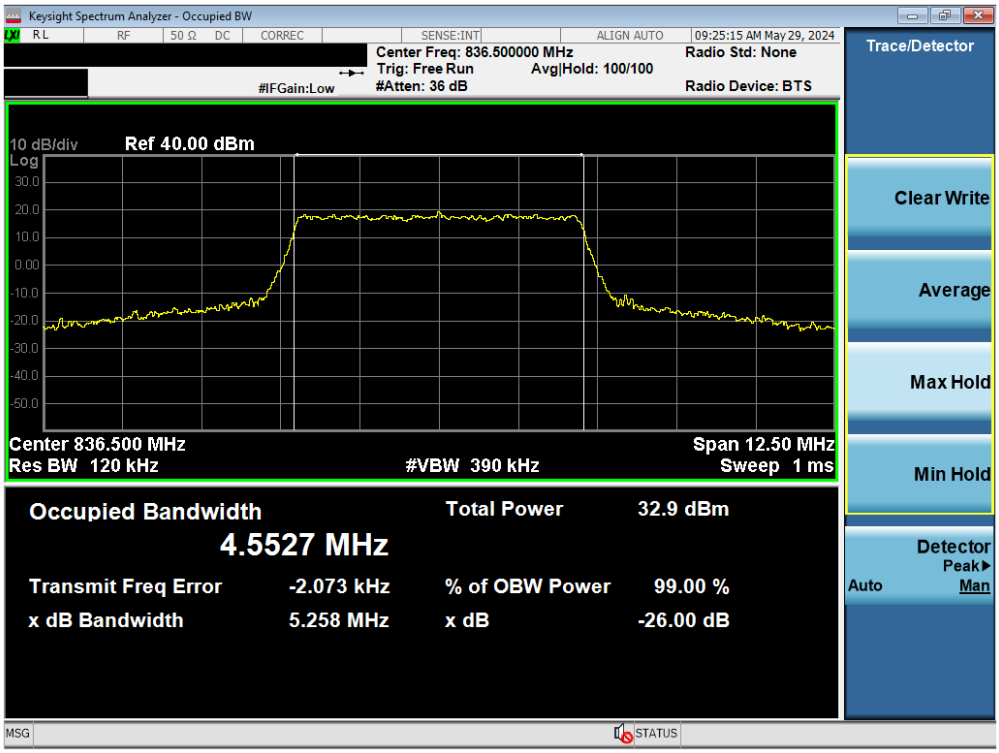
Plot 7-9. Occupied Bandwidth Plot (LTE Band 26/5 - 5MHz QPSK - Full RB Configuration)



Plot 7-10. Occupied Bandwidth Plot (LTE Band 26/5 - 5MHz 16-QAM - Full RB Configuration)

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Plot 7-11. Occupied Bandwidth Plot (LTE Band 26/5 - 5MHz 64-QAM - Full RB Configuration)

Plot 7-12. Occupied Bandwidth Plot (LTE Band 26/5 - 5MHz 256-QAM - Full RB Configuration)

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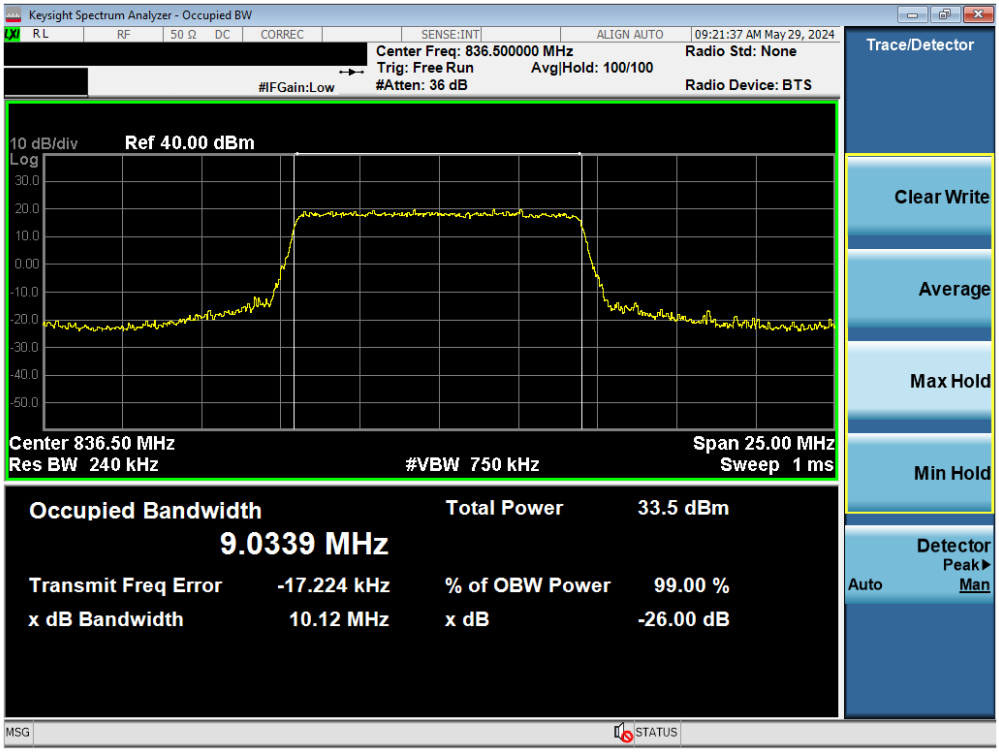
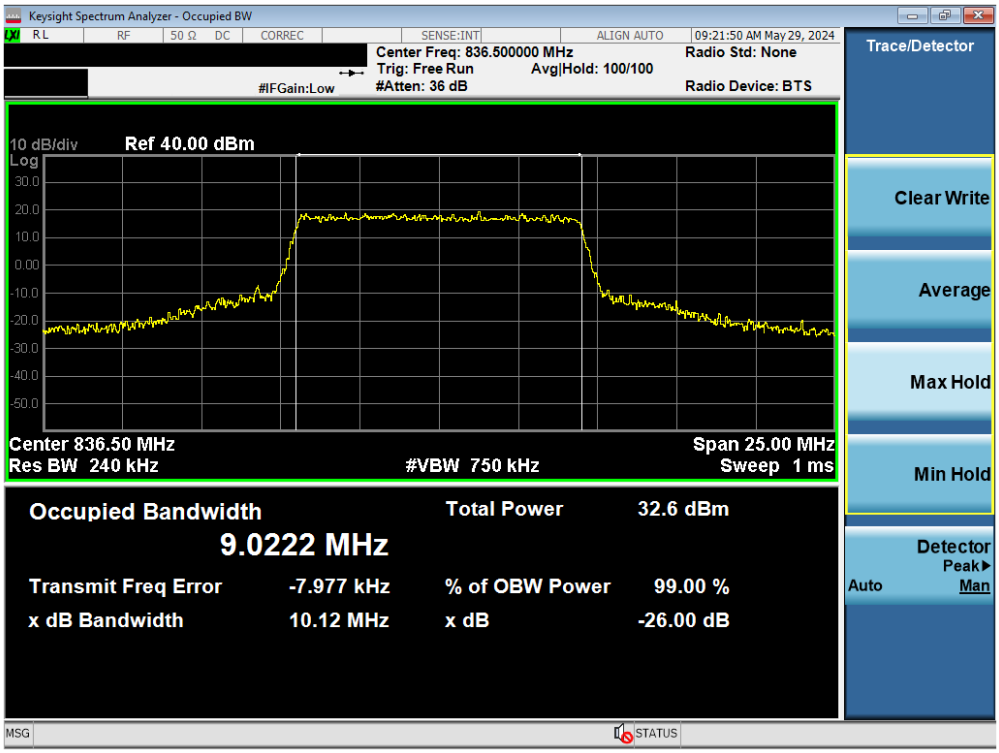


Plot 7-13. Occupied Bandwidth Plot (LTE Band 26/5 - 10MHz QPSK - Full RB Configuration)



Plot 7-14. Occupied Bandwidth Plot (LTE Band 26/5 - 10MHz 16-QAM - Full RB Configuration)

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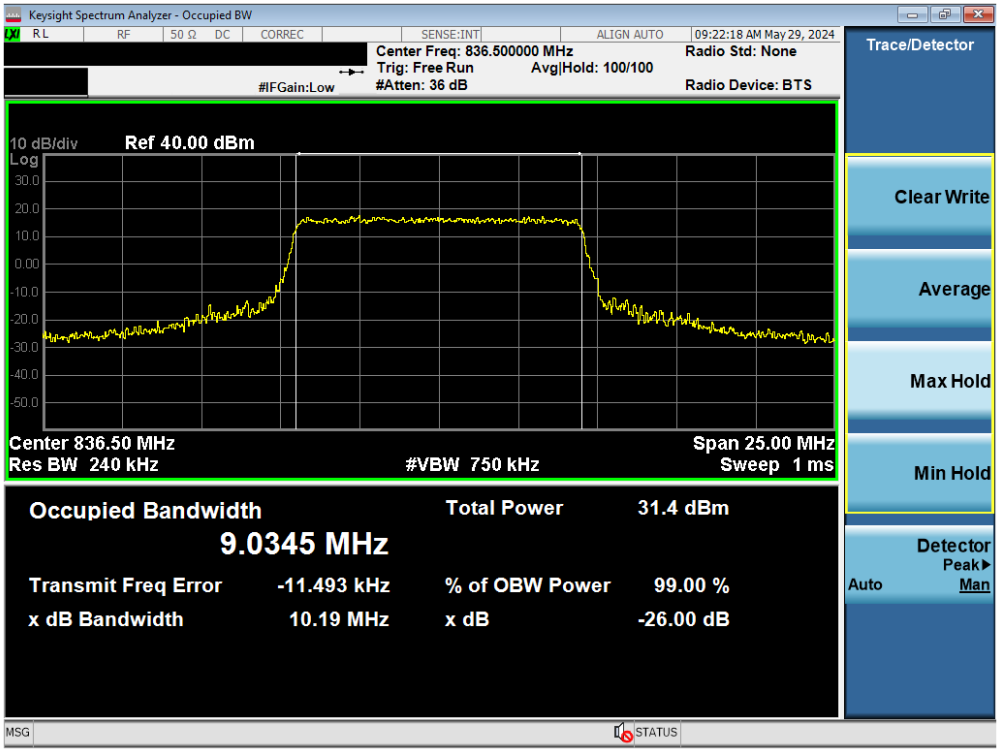
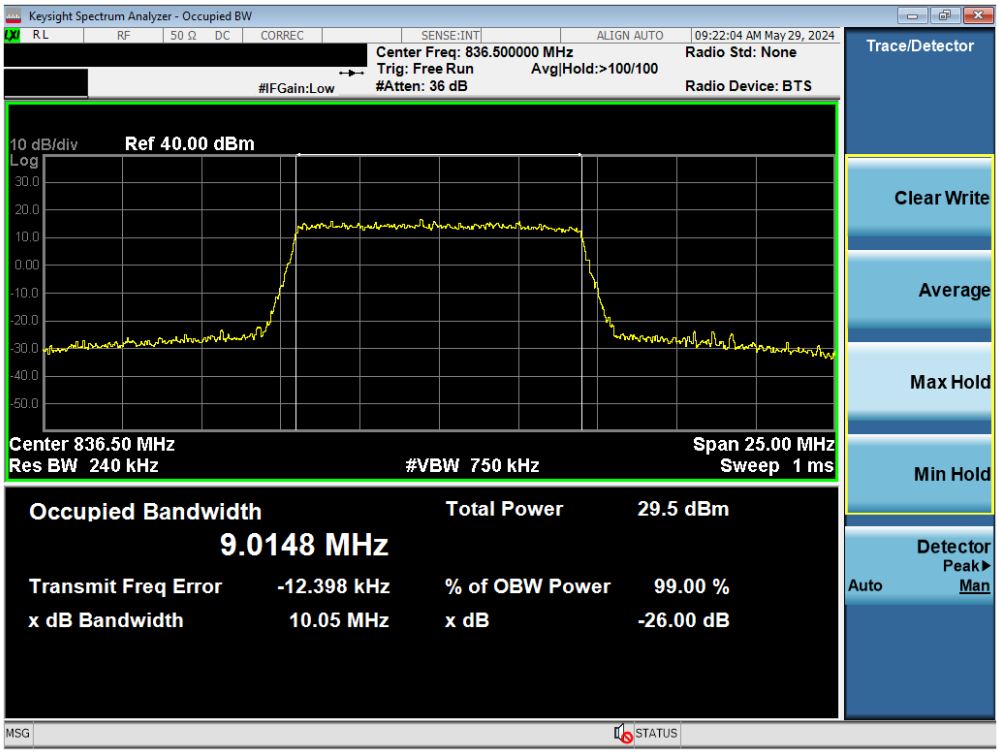


Plot 7-15. Occupied Bandwidth Plot (LTE Band 26/5 - 10MHz 64-QAM - Full RB Configuration)



Plot 7-16. Occupied Bandwidth Plot (LTE Band 26/5 - 10MHz 256-QAM - Full RB Configuration)

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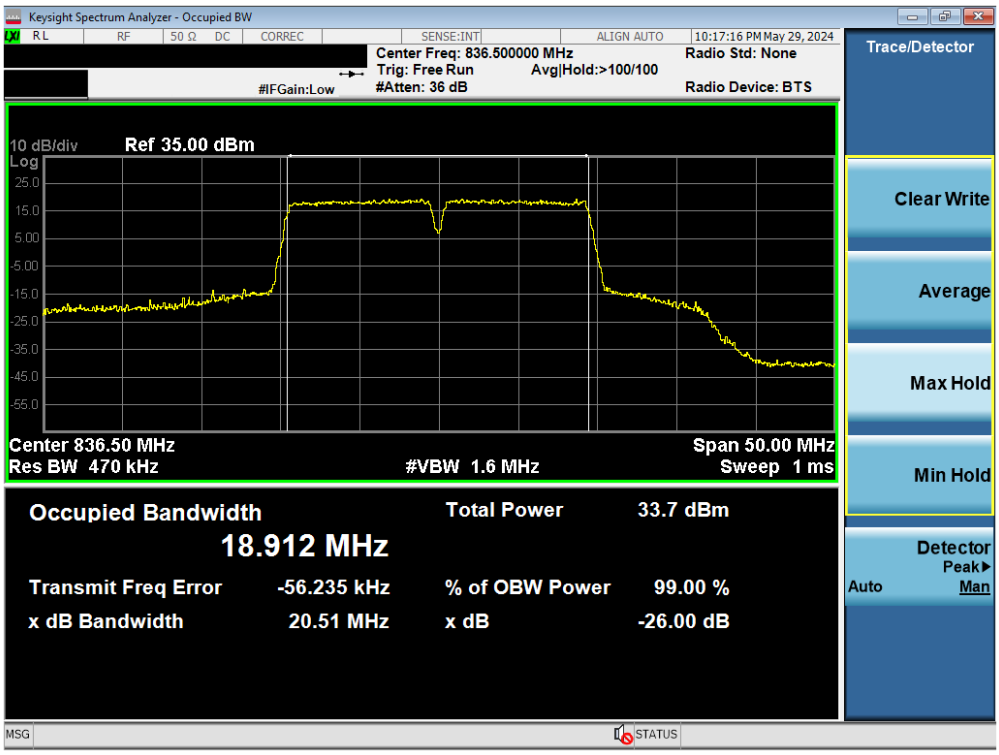
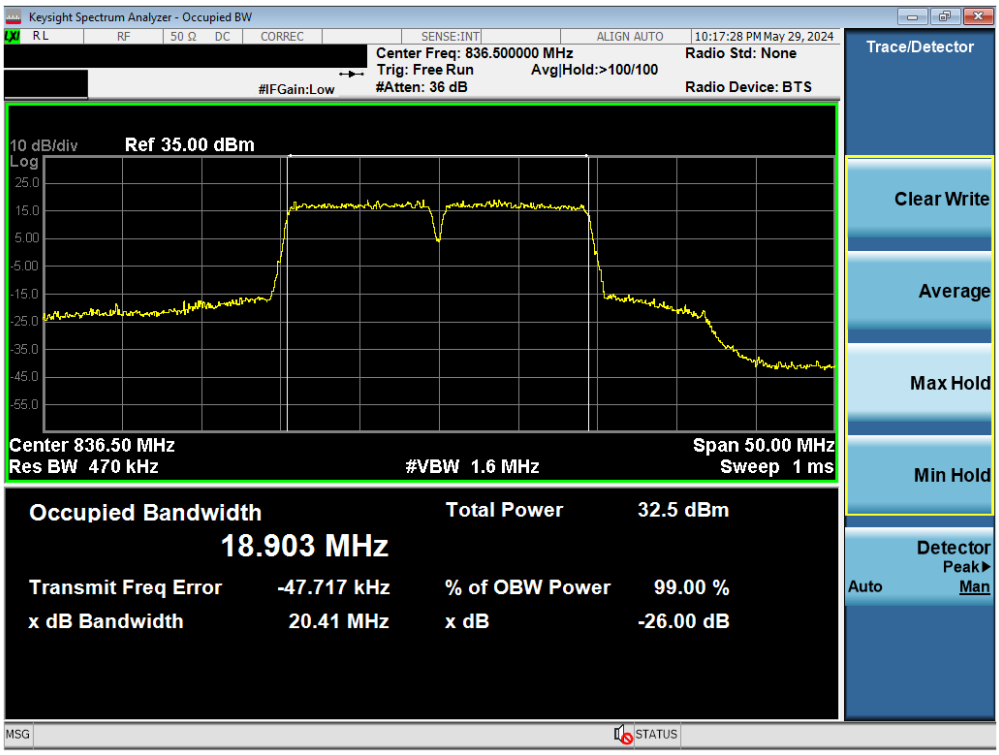
ULCA – LTE Band 5



Plot 7-17. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz QPSK - Full RB Configuration)



Plot 7-18. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz 16-QAM - Full RB Configuration)

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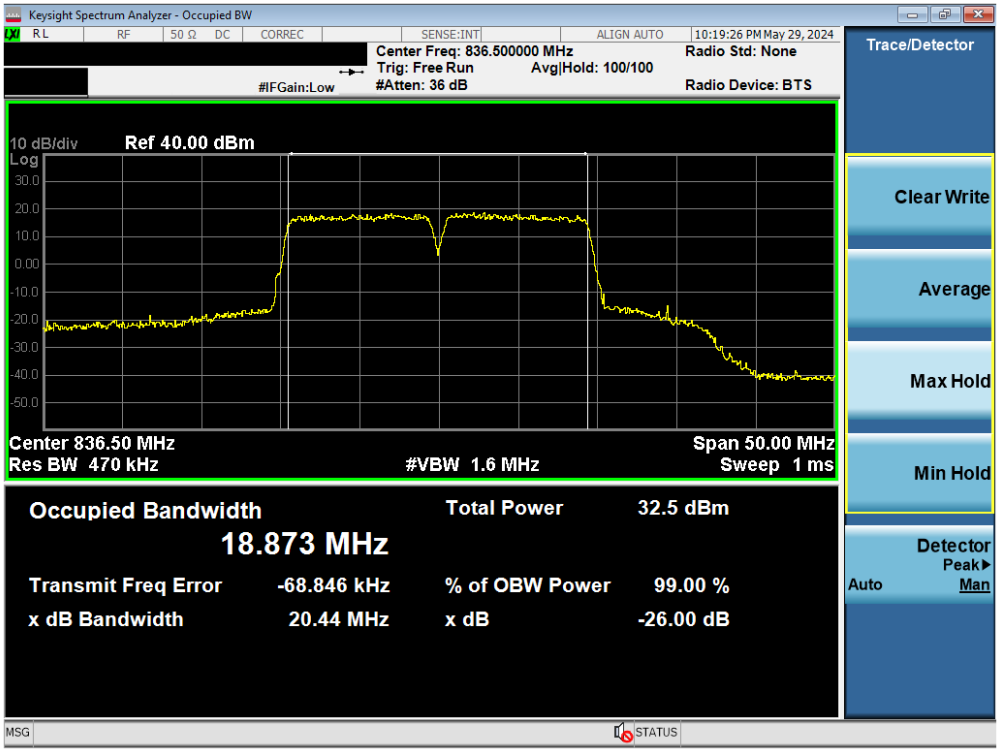
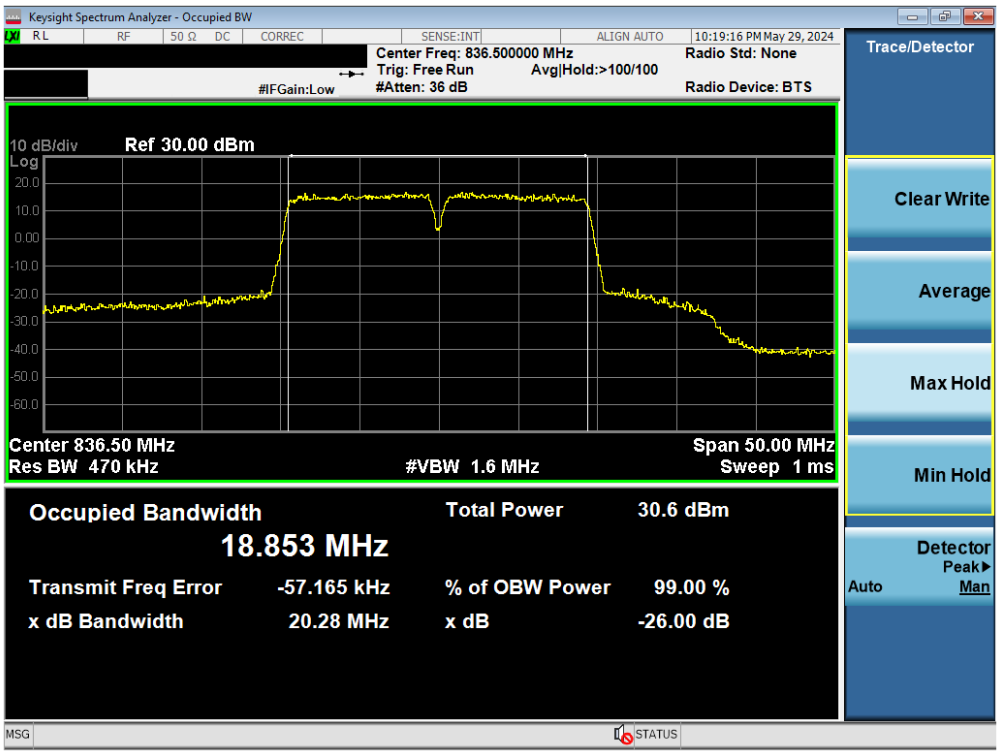


Plot 7-19. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz 64-QAM - Full RB Configuration)



Plot 7-20. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz 256-QAM - Full RB Configuration)

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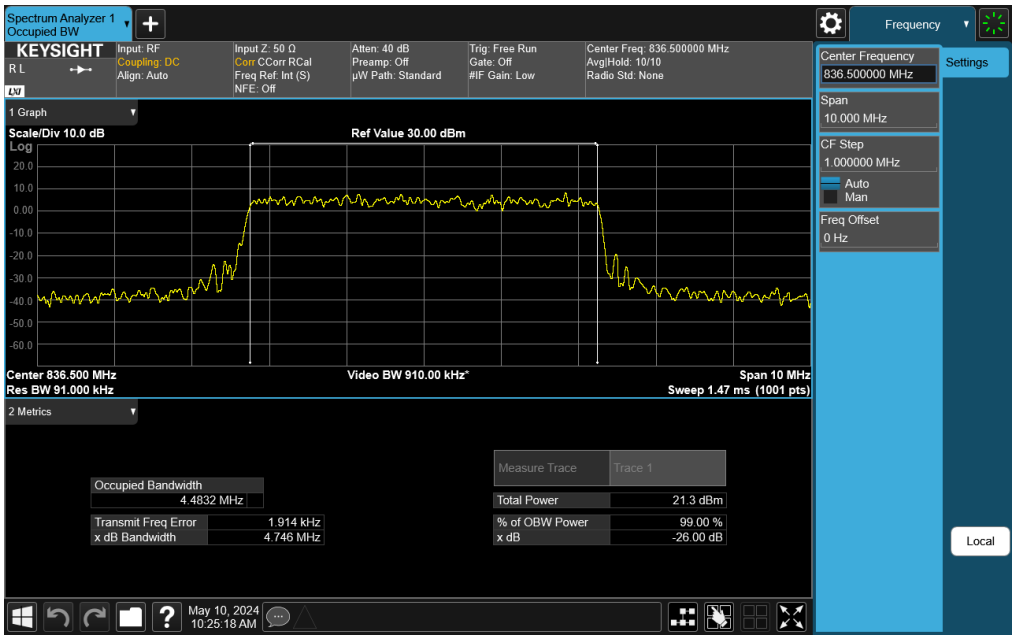
NR Band n26/n5

Plot 7-21. Occupied Bandwidth Plot (NR Band n26/n5 - 5MHz n5 DFT-s-OFDM π/2 BPSK - Full RB Configuration)



Plot 7-22. Occupied Bandwidth Plot (NR Band n26/n5 - 5MHz CP-OFDM QPSK - Full RB Configuration)

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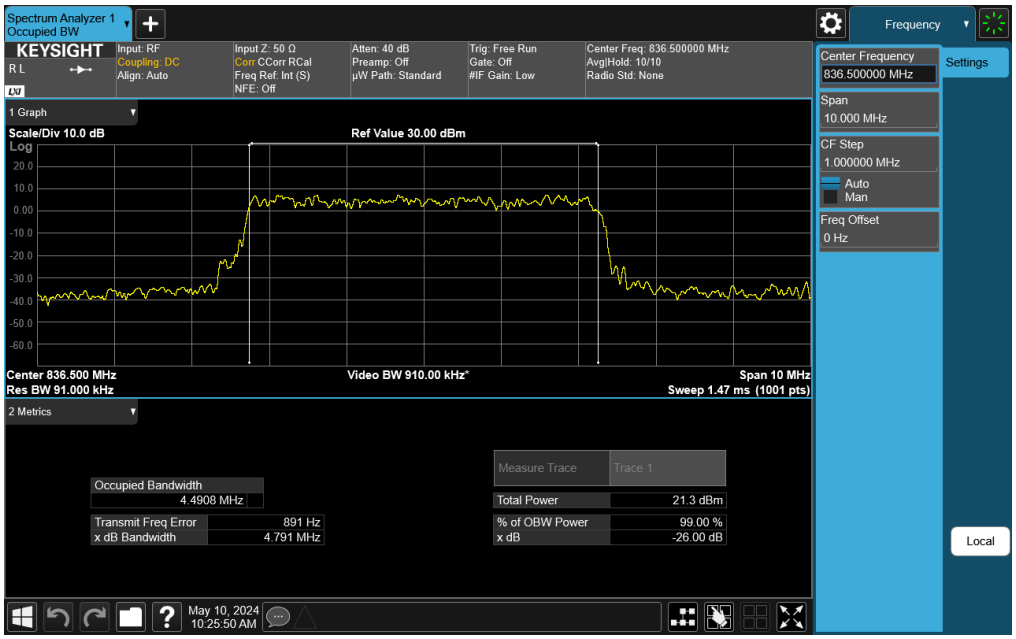
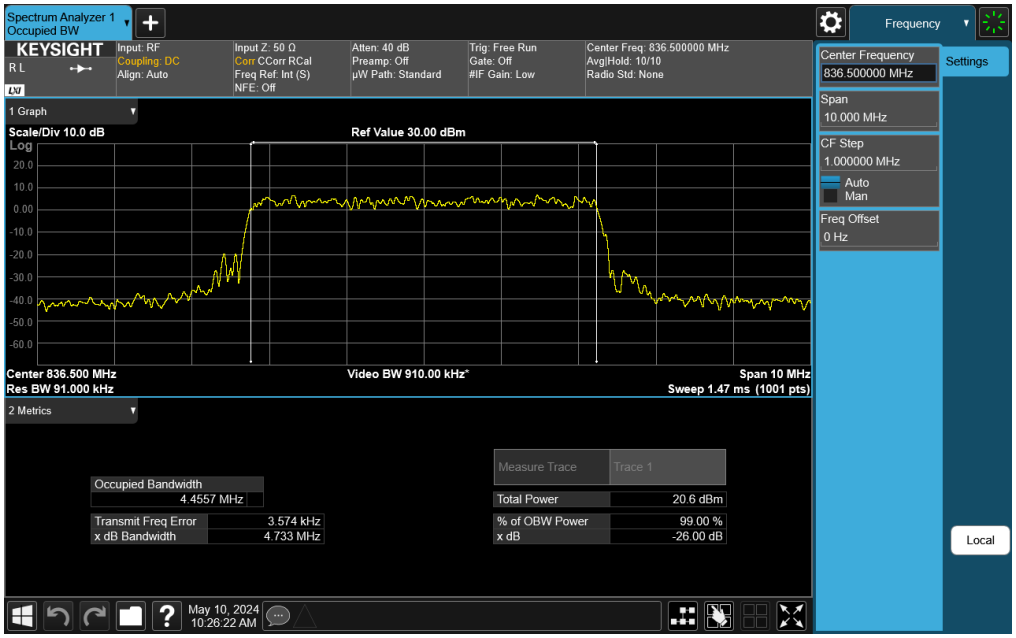


Plot 7-23. Occupied Bandwidth Plot (NR Band n26/n5 - 5MHz CP-OFDM 16-QAM - Full RB Configuration)



Plot 7-24. Occupied Bandwidth Plot (NR Band n26/n5 - 5MHz CP-OFDM 64-QAM - Full RB Configuration)

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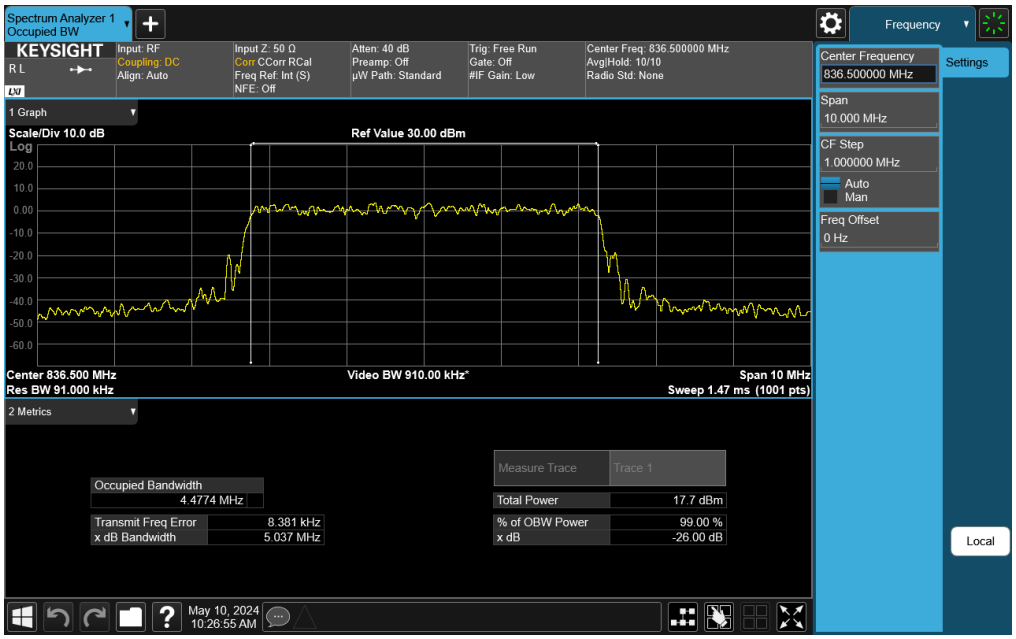
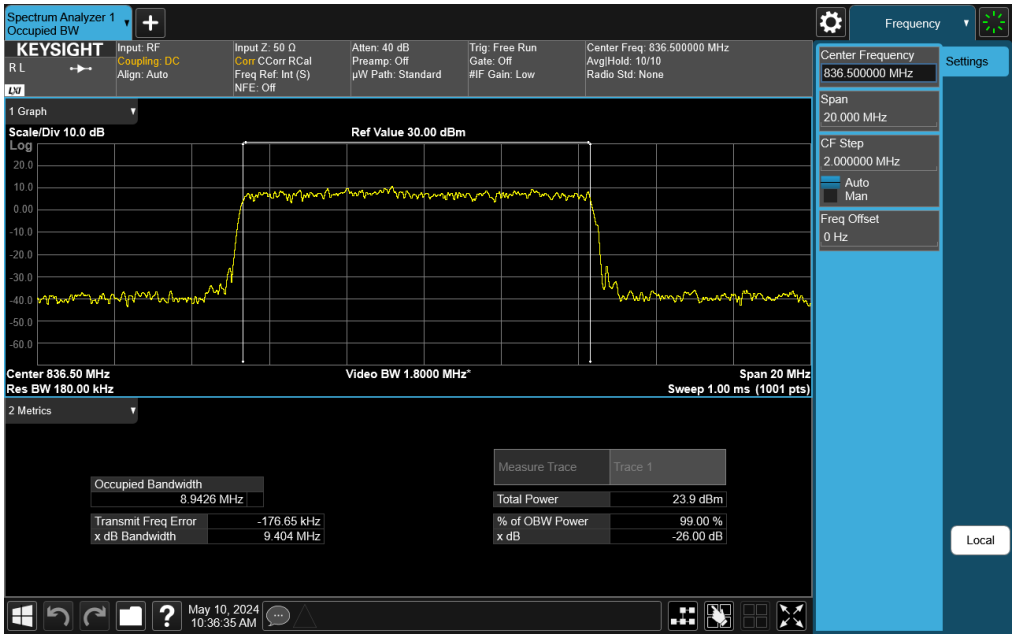


Plot 7-25. Occupied Bandwidth Plot (NR Band n26/n5 - 5MHz CP-OFDM 256-QAM - Full RB Configuration)



Plot 7-26. Occupied Bandwidth Plot (NR Band n26/n5 - 10MHz DFT-s-OFDM π/2 BPSK - Full RB Configuration)

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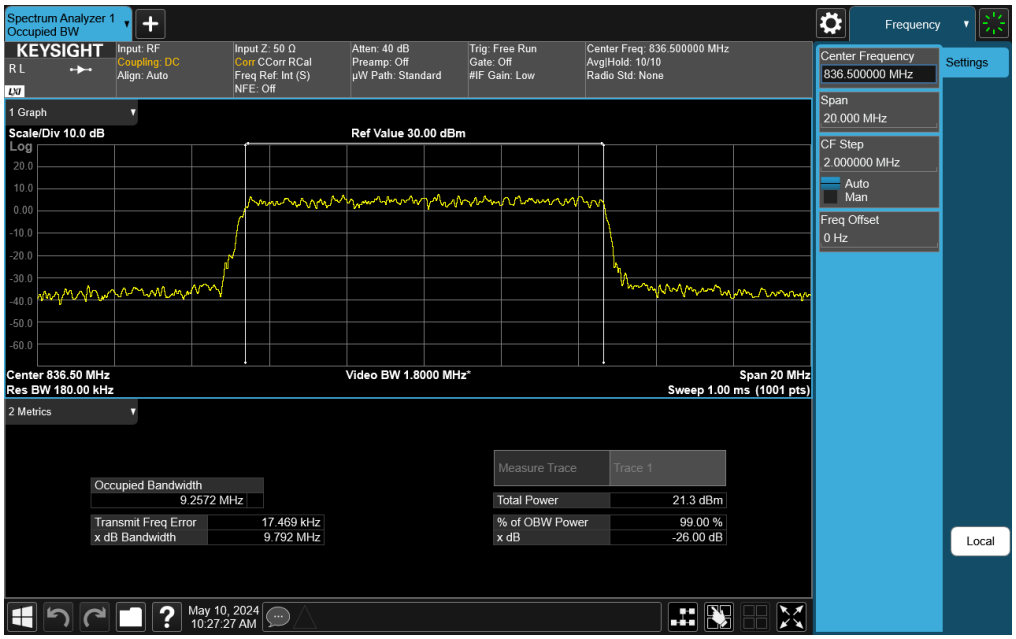
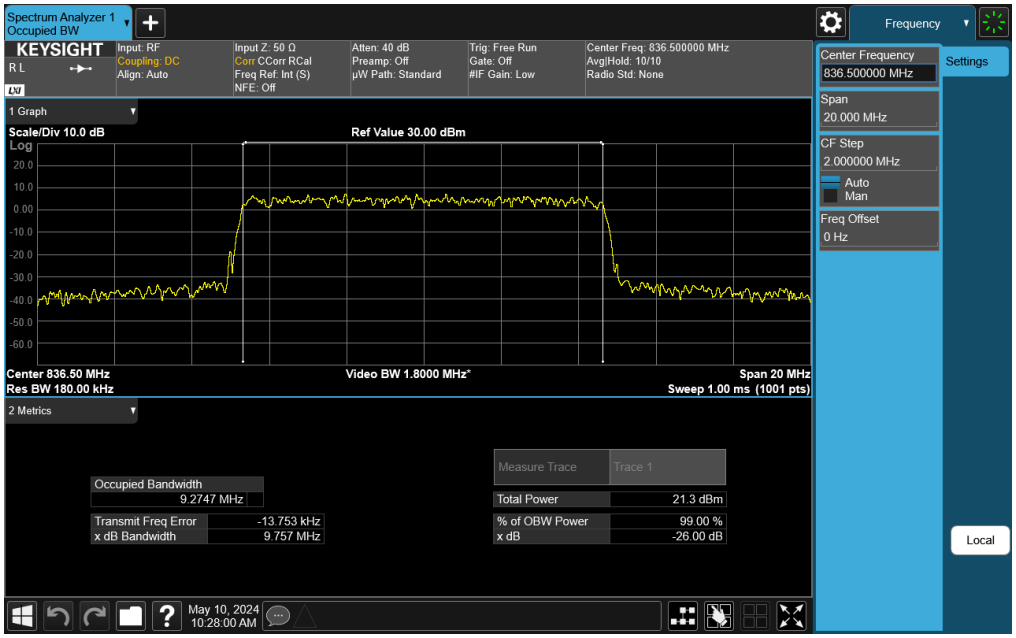


Plot 7-27. Occupied Bandwidth Plot (NR Band n26/n5 - 10MHz CP-OFDM QPSK - Full RB Configuration)



Plot 7-28. Occupied Bandwidth Plot (NR Band n26/n5 - 10MHz CP-OFDM 16-QAM - Full RB Configuration)

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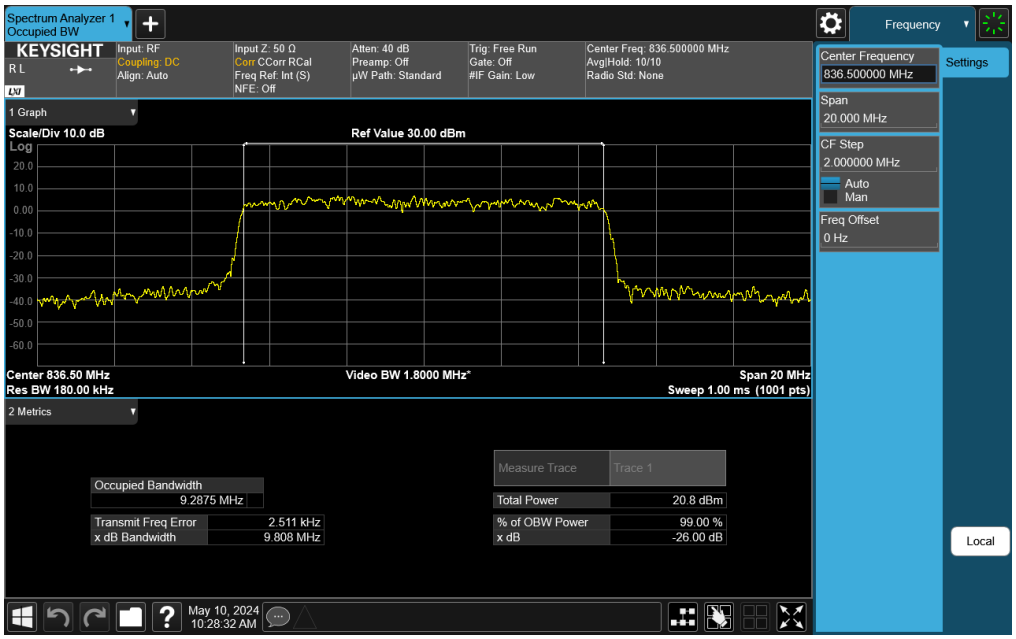
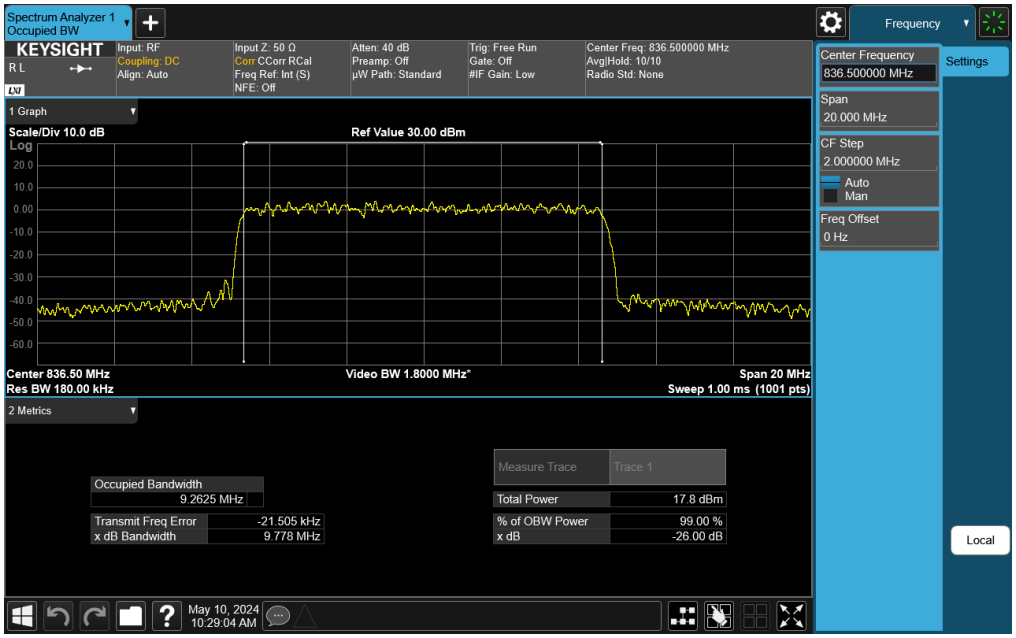


Plot 7-29. Occupied Bandwidth Plot (NR Band n26/n5 - 10MHz CP-OFDM 64-QAM - Full RB Configuration)



Plot 7-30. Occupied Bandwidth Plot (NR Band n26/n5 - 10MHz CP-OFDM 256-QAM - Full RB Configuration)

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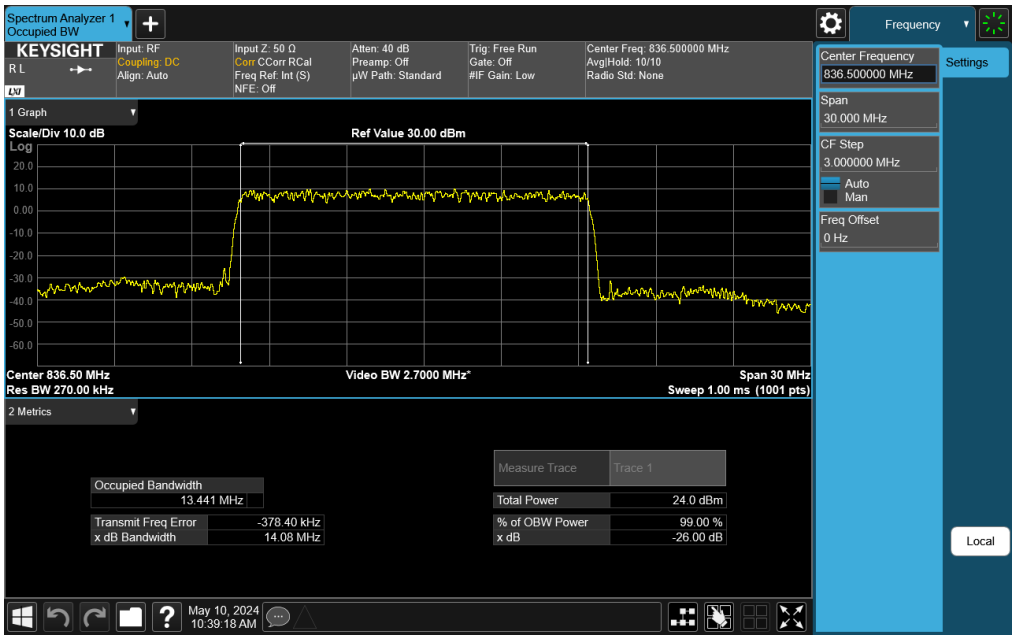
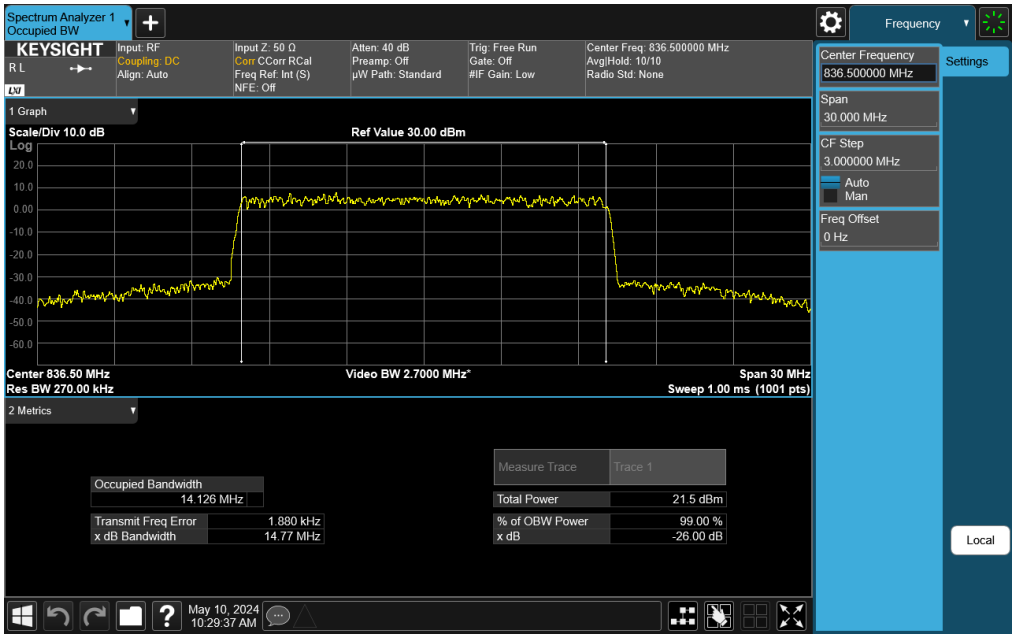


Plot 7-31. Occupied Bandwidth Plot (NR Band n26/n5 - 15MHz DFT-s-OFDM π/2 BPSK - Full RB Configuration)



Plot 7-32. Occupied Bandwidth Plot (NR Band n26/n5 - 15MHz CP-OFDM QPSK - Full RB Configuration)

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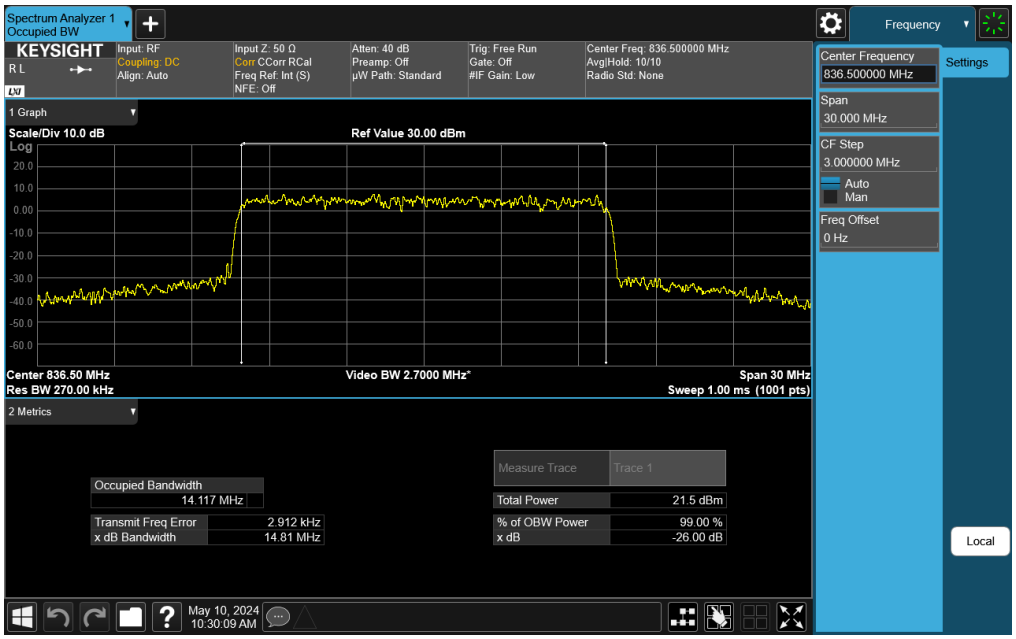
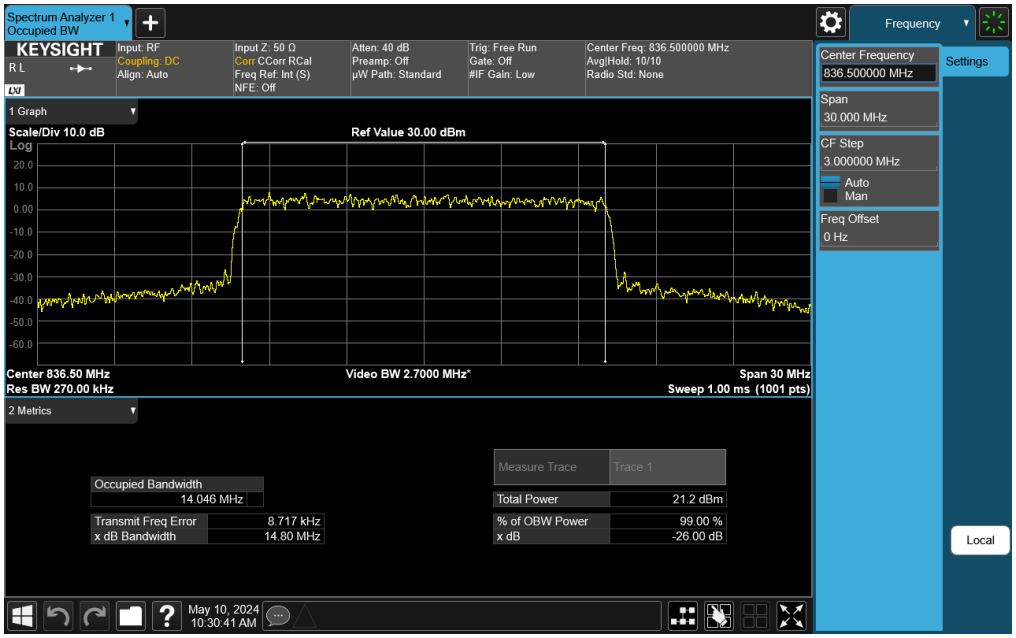


Plot 7-33. Occupied Bandwidth Plot (NR Band n26/n5 - 15MHz CP-OFDM 16-QAM - Full RB Configuration)



Plot 7-34. Occupied Bandwidth Plot (NR Band n26/n5 - 15MHz CP-OFDM 64-QAM - Full RB Configuration)

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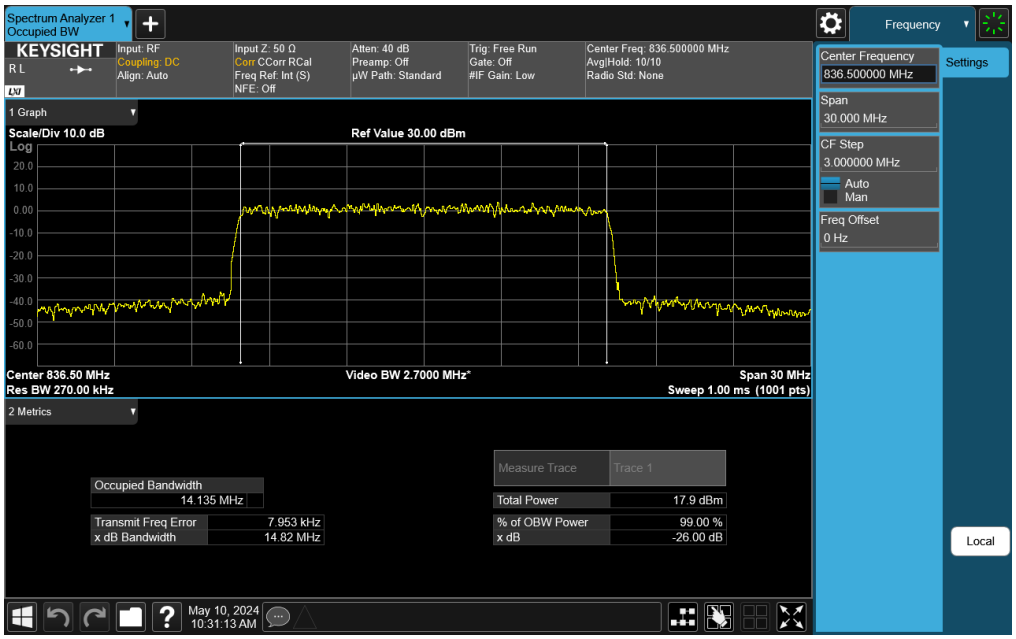
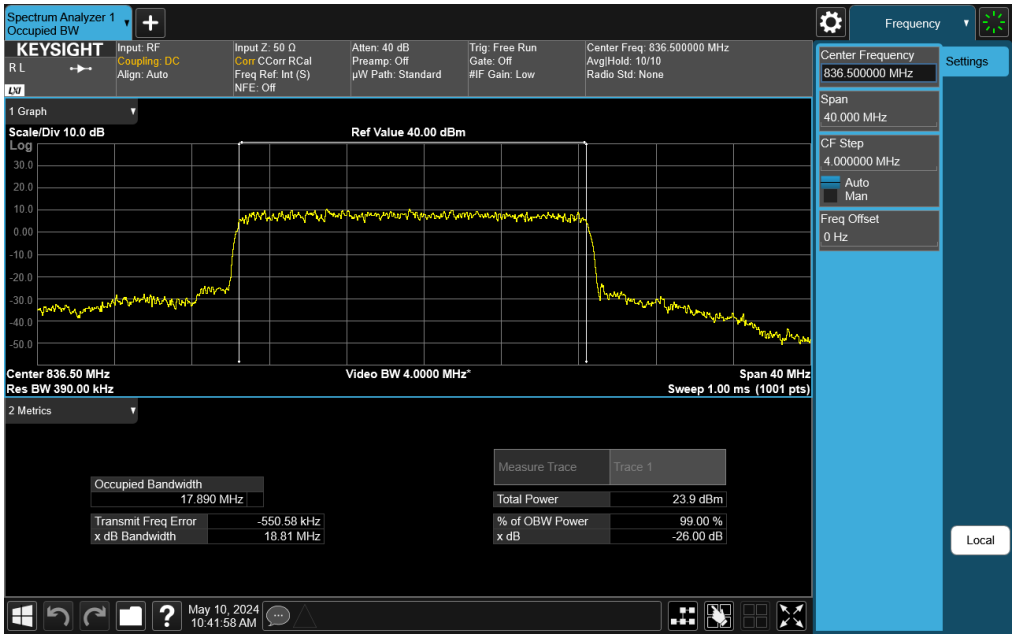


Plot 7-35. Occupied Bandwidth Plot (NR Band n26/n5 - 15MHz CP-OFDM 256-QAM - Full RB Configuration)



Plot 7-36. Occupied Bandwidth Plot (NR Band n26/n5 - 20MHz DFT-s-OFDM π/2 BPSK - Full RB Configuration)

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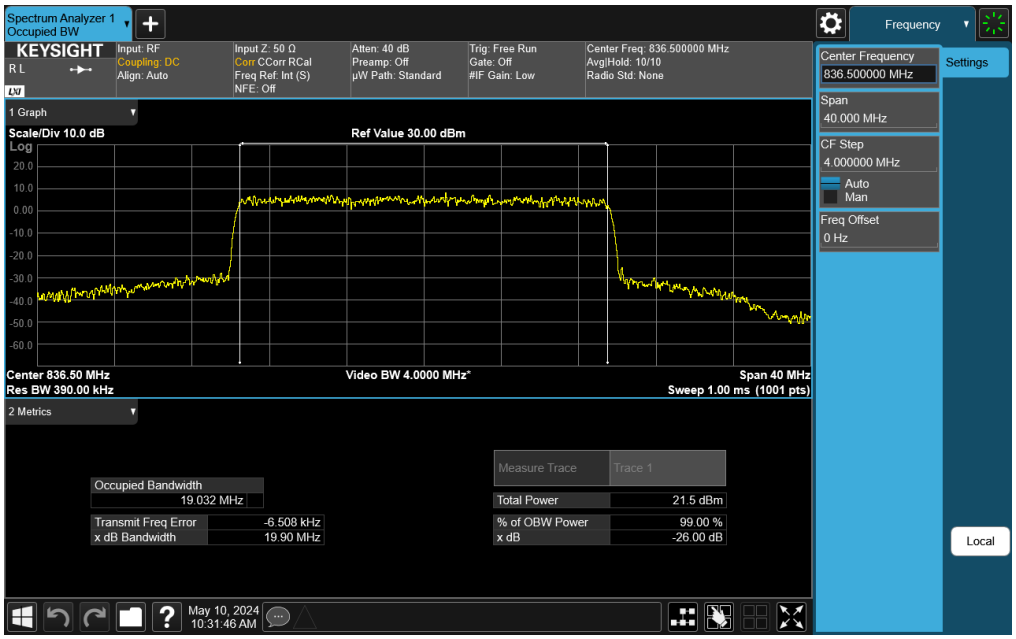
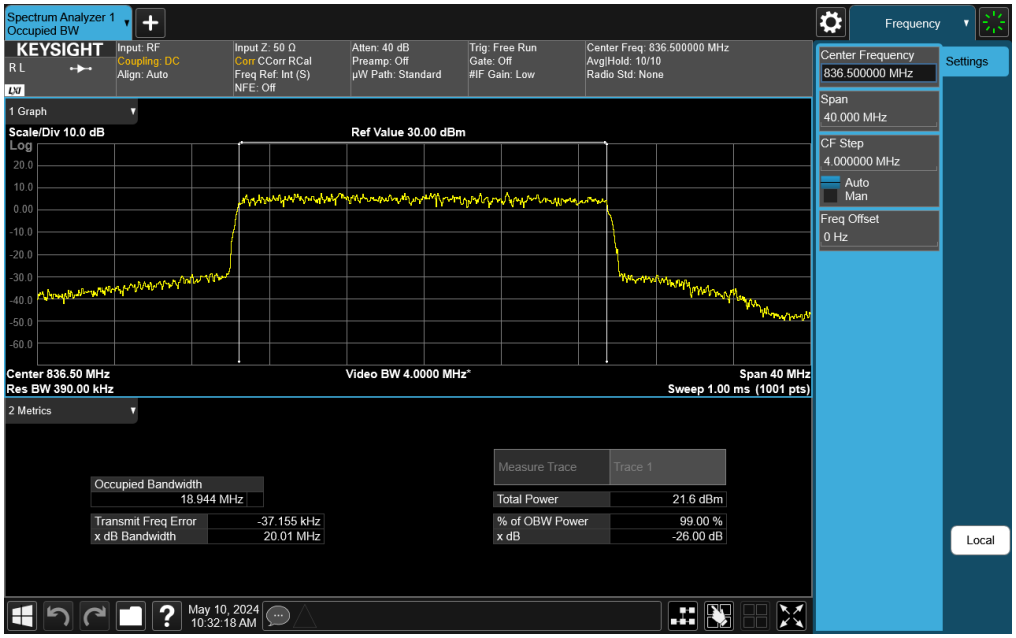


Plot 7-37. Occupied Bandwidth Plot (NR Band n26/n5 - 20MHz CP-OFDM QPSK - Full RB Configuration)



Plot 7-38. Occupied Bandwidth Plot (NR Band n26/n5 - 20MHz CP-OFDM 16-QAM - Full RB Configuration)

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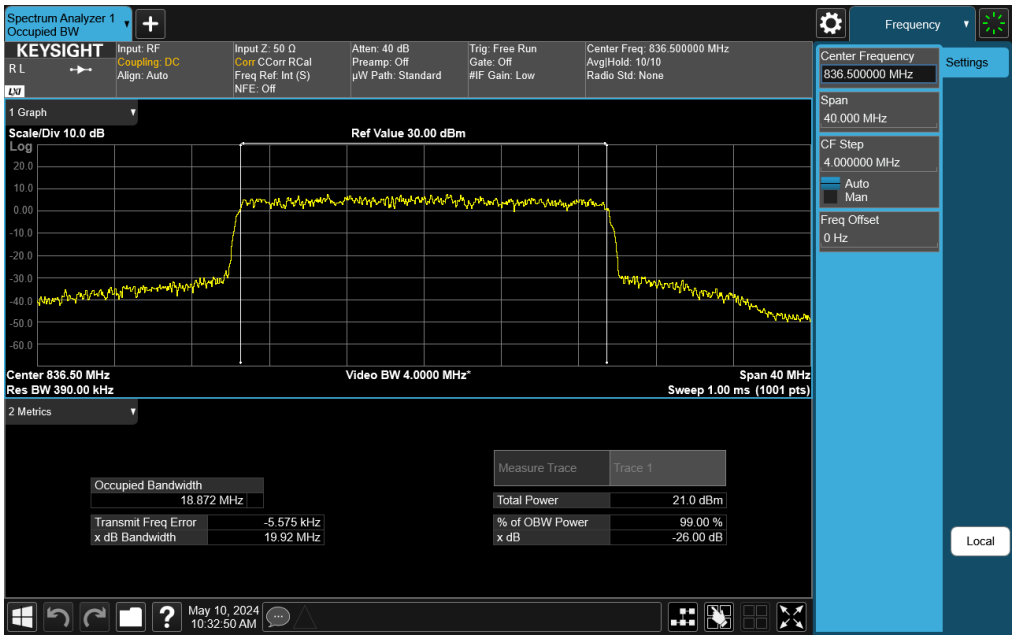
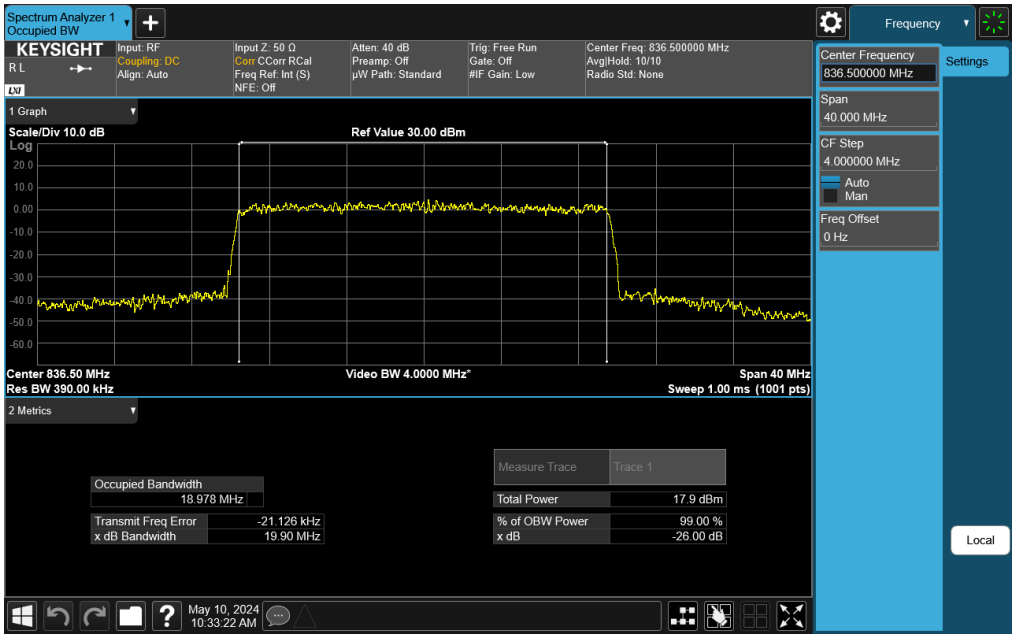


Plot 7-39. Occupied Bandwidth Plot (NR Band n26/n5 - 20MHz CP-OFDM 64-QAM - Full RB Configuration)



Plot 7-40. Occupied Bandwidth Plot (NR Band n26/n5 - 20MHz CP-OFDM 256-QAM - Full RB Configuration)

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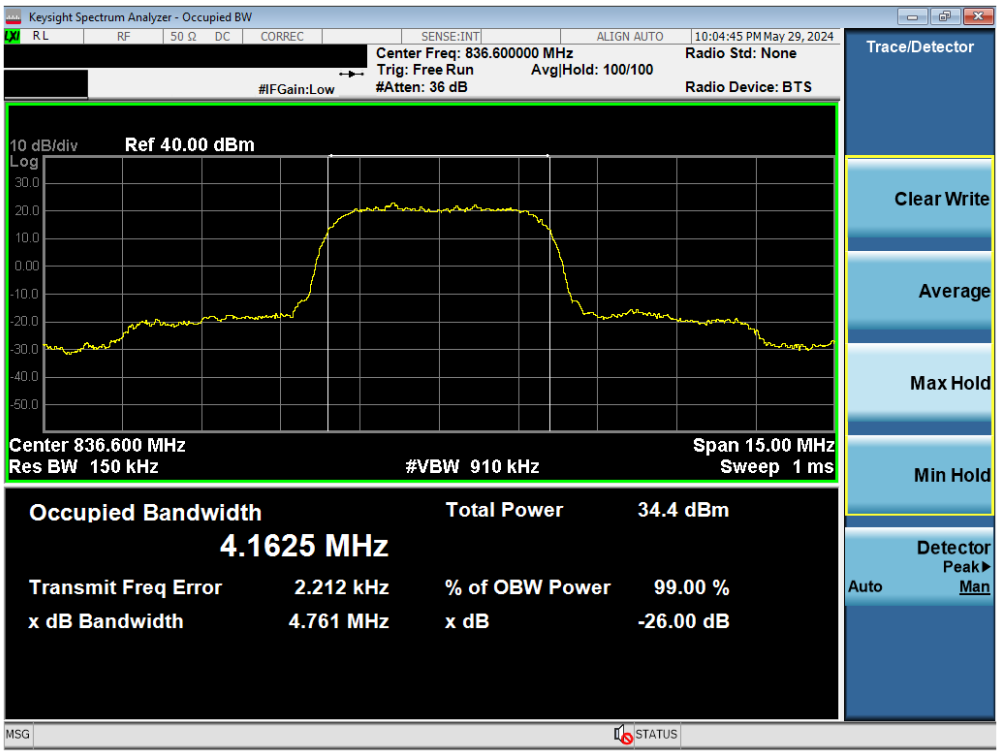
WCDMA Cell



Plot 7-41. Occupied Bandwidth Plot (WCDMA, Ch. 4183)

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7.3 Spurious and Harmonic Emissions at Antenna Terminal

§2.1051, 22.917(a)

Test Overview and Limit

The level of the carrier and the various conducted spurious and harmonic frequencies is measured by means of a calibrated spectrum analyzer. The spectrum is scanned from the lowest frequency generated in the equipment up to a frequency including its 10th harmonic. All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section. All ports were tested and only the worst case data were reported.

The minimum permissible attenuation level of any spurious emission is 43 + 10 $\log_{10}(P_{[Watts]})$, where P is the transmitter power in Watts.

Test Procedure Used

KDB 971168 D01 v03r01 – Section 6.0

Test Settings

1. Start frequency was set to 30MHz and stop frequency was set to 10GHz (separated into at least two plots per channel)
2. Detector = RMS
3. Trace mode = trace average for continuous emissions, max hold for pulse emissions
4. Sweep time = auto couple
5. The trace was allowed to stabilize
6. Please see test notes below for RBW and VBW settings

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

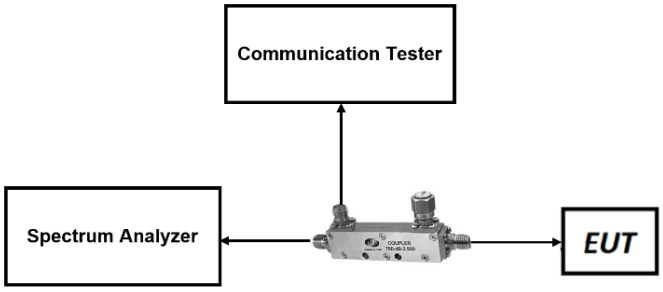

Figure 7-3. LTE Test Instrument & Measurement Setup

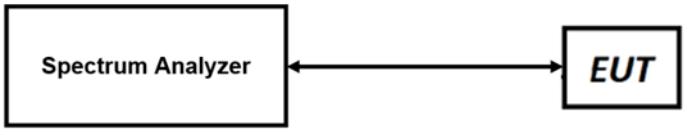

Figure 7-4. FR1 Test Instrument & Measurement Setup

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Test Notes

1. Per Part 22, compliance with the applicable limits is based on the use of measurement instrumentation employing a resolution bandwidth 100 kHz or greater for measurements below 1GHz. However, in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power.

2. For NR operation, all subcarrier spacings (SCS) and transmission schemes (e.g. CP-OFDM and DFT-s-OFDM) were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

3. Uplink carrier aggregation conducted spurious emissions measurements were evaluated for the two contiguous channels using various combinations of RB size, RB offset, modulation, and channel bandwidth. The worst case (highest) powers were found while operating with QPSK modulation with both carriers set to transmit using 1RB.

4. Uplink carrier aggregation inter-band emission was investigated and found to not be the worst case

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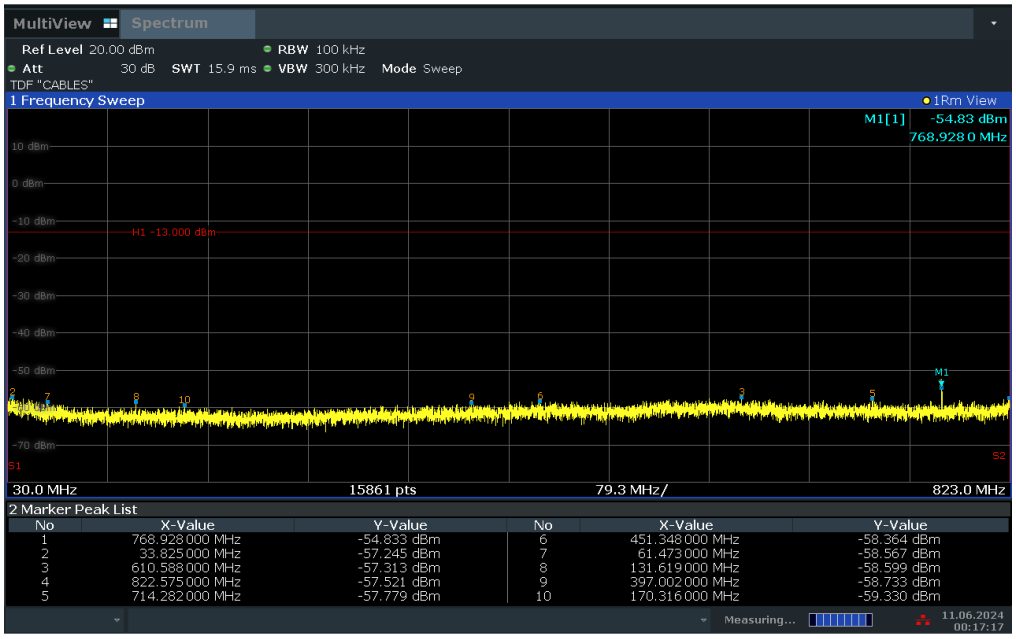
LTE Band 26/5

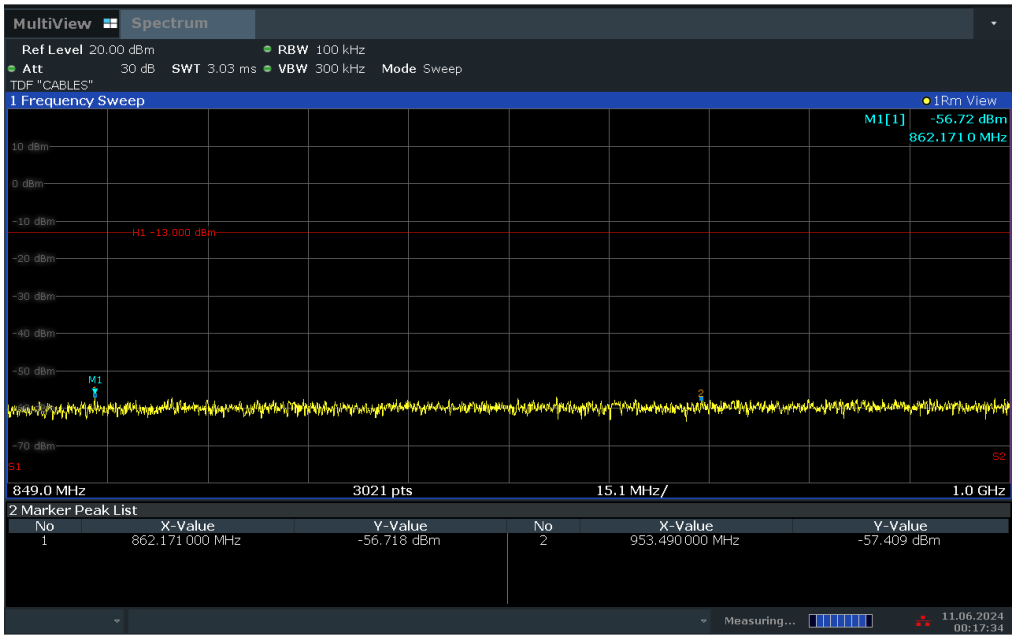
ACLRResults



00:17:17 11.06.2024

Plot 7-42. Conducted Spurious Plot (LTE Band 26/5 - 10MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

ACLRResults



00:17:35 11.06.2024

Plot 7-43. Conducted Spurious Plot (LTE Band 26/5 - 10MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

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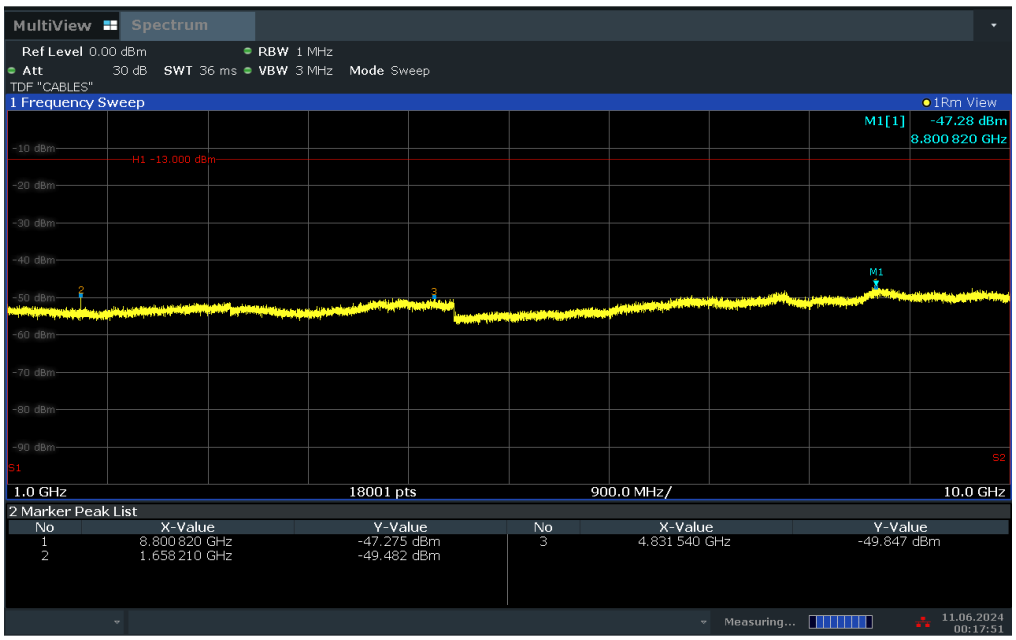
ACLRResults



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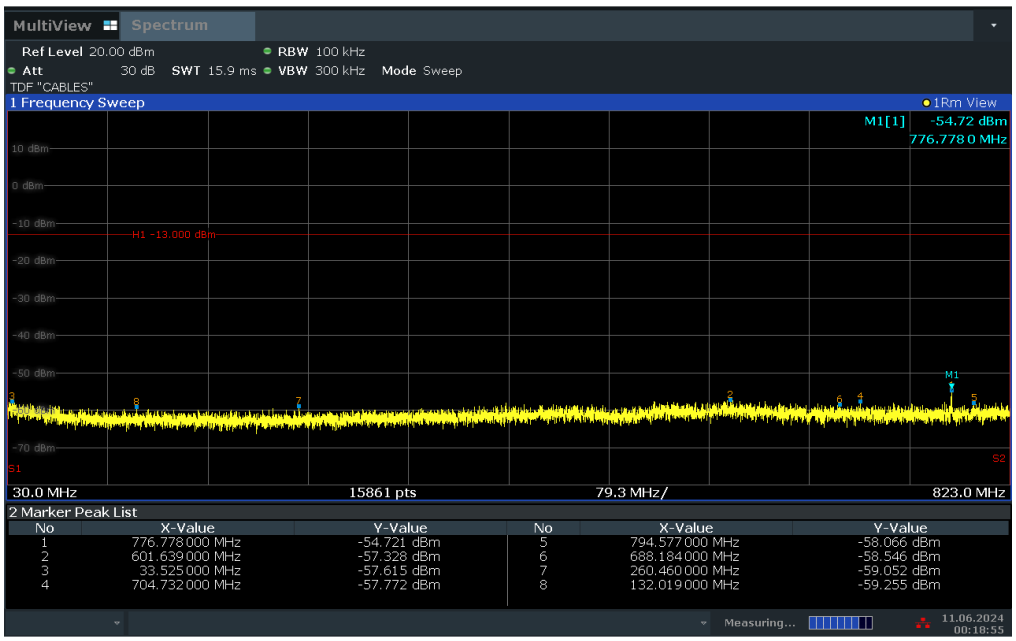
Plot 7-44. Conducted Spurious Plot (LTE Band 26/5 - 10MHz QPSK - RB Size 1, RB Offset 0 - Low Channel)

ACLRResults



00:18:56 11.06.2024

Plot 7-45. Conducted Spurious Plot (LTE Band 26/5 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

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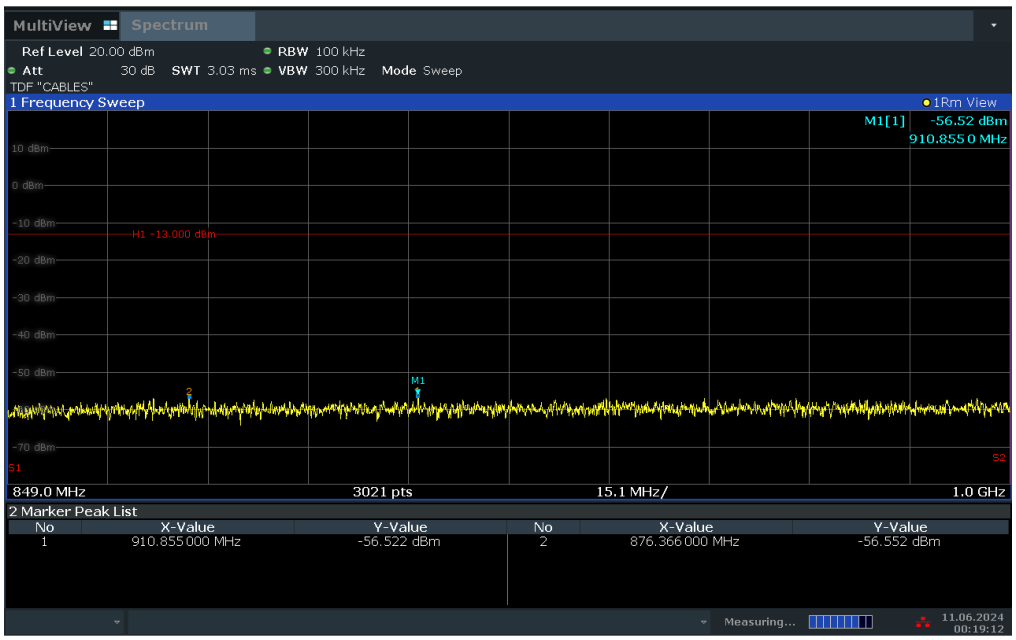
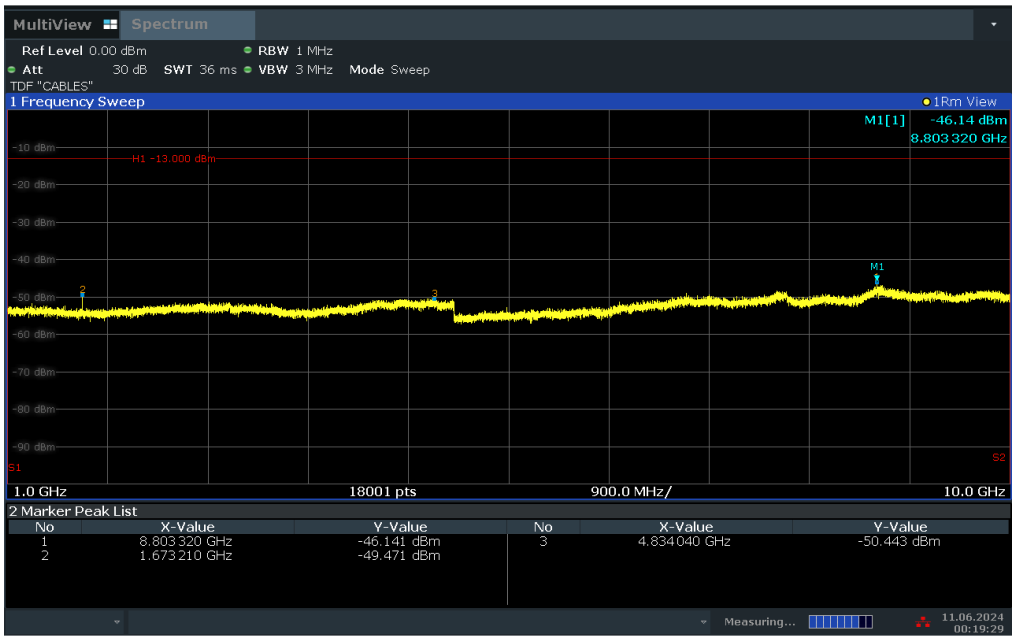
ACLRResults



00:19:13 11.06.2024

Plot 7-46. Conducted Spurious Plot (LTE Band 26/5 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

ACLRResults



00:19:30 11.06.2024

Plot 7-47. Conducted Spurious Plot (LTE Band 26/5 - 10MHz QPSK - RB Size 1, RB Offset 0 - Mid Channel)

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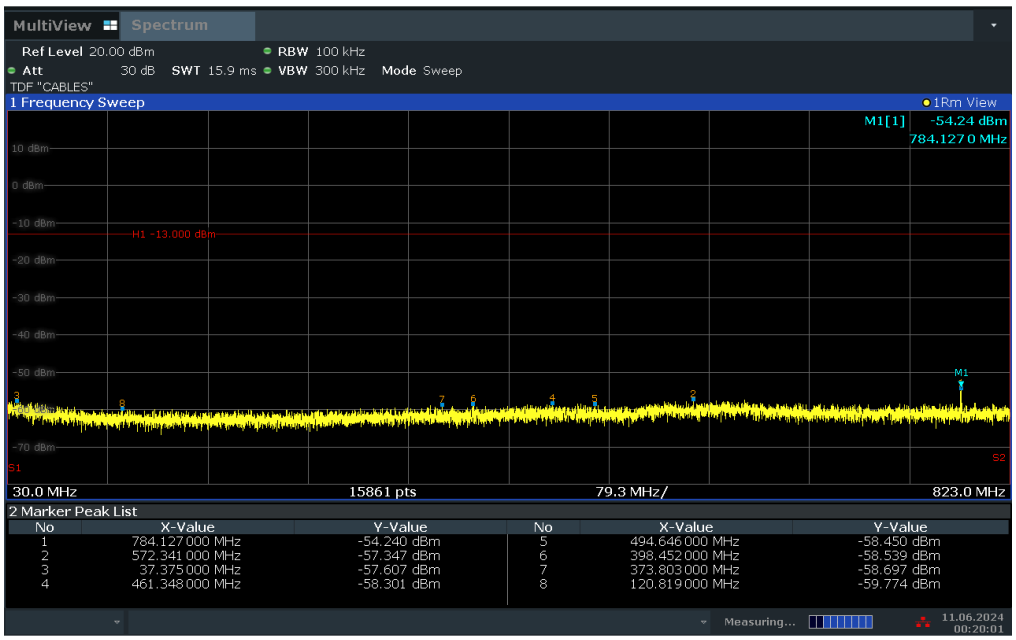
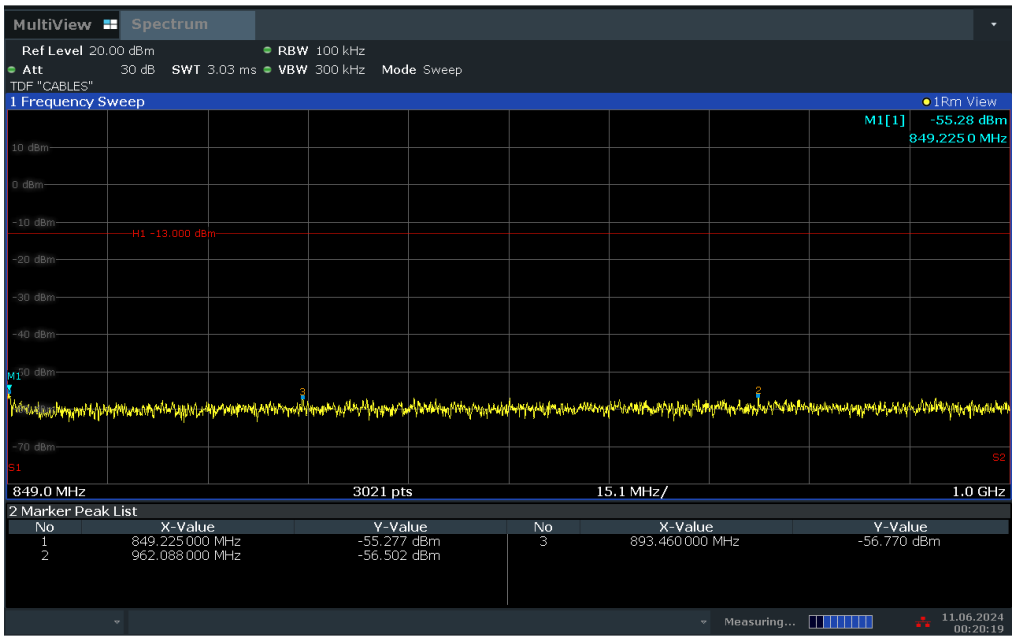
ACLRResults



00:20:02 11.06.2024

Plot 7-48. Conducted Spurious Plot (LTE Band 26/5 - 10MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

ACLRResults



00:20:19 11.06.2024

Plot 7-49. Conducted Spurious Plot (LTE Band 26/5 - 10MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

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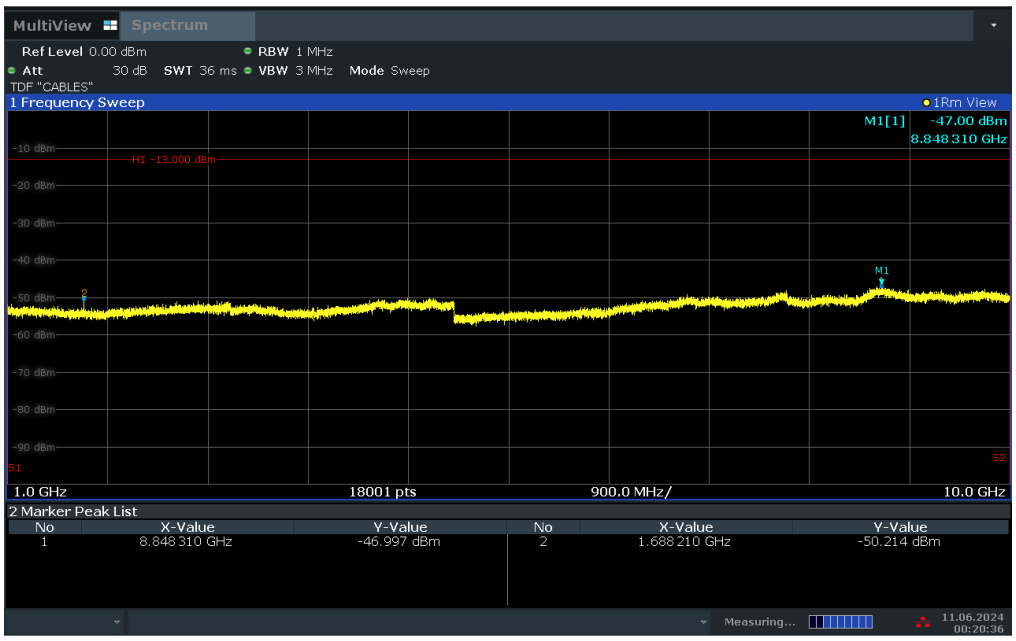
ACLRResults



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Plot 7-50. Conducted Spurious Plot (LTE Band 26/5 - 10MHz QPSK - RB Size 1, RB Offset 0 - High Channel)

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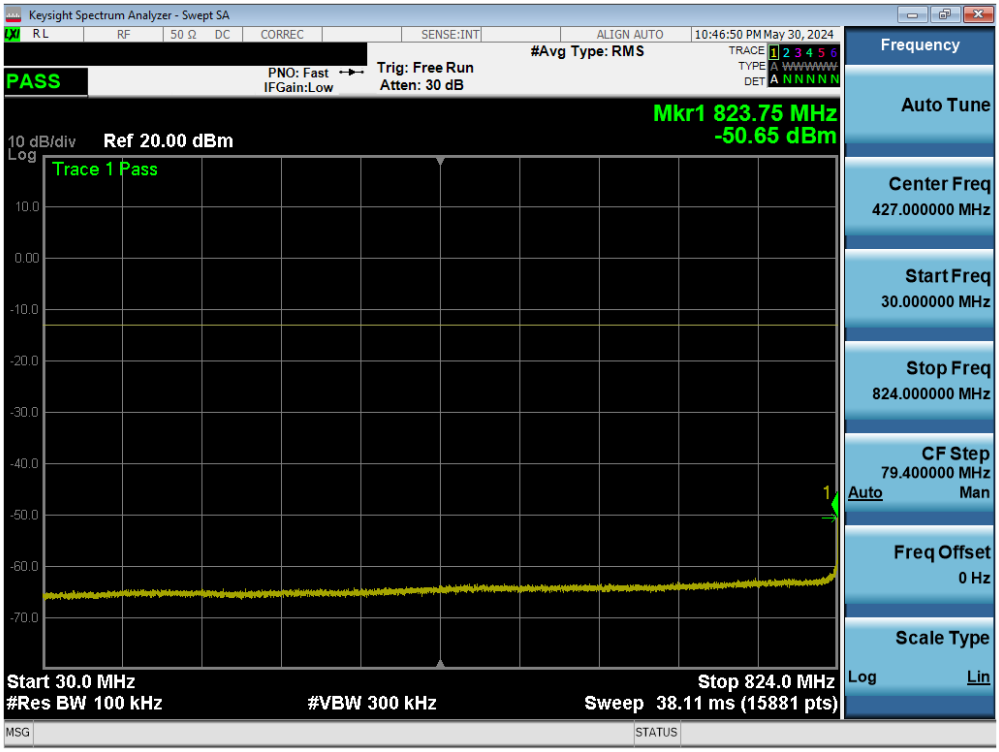
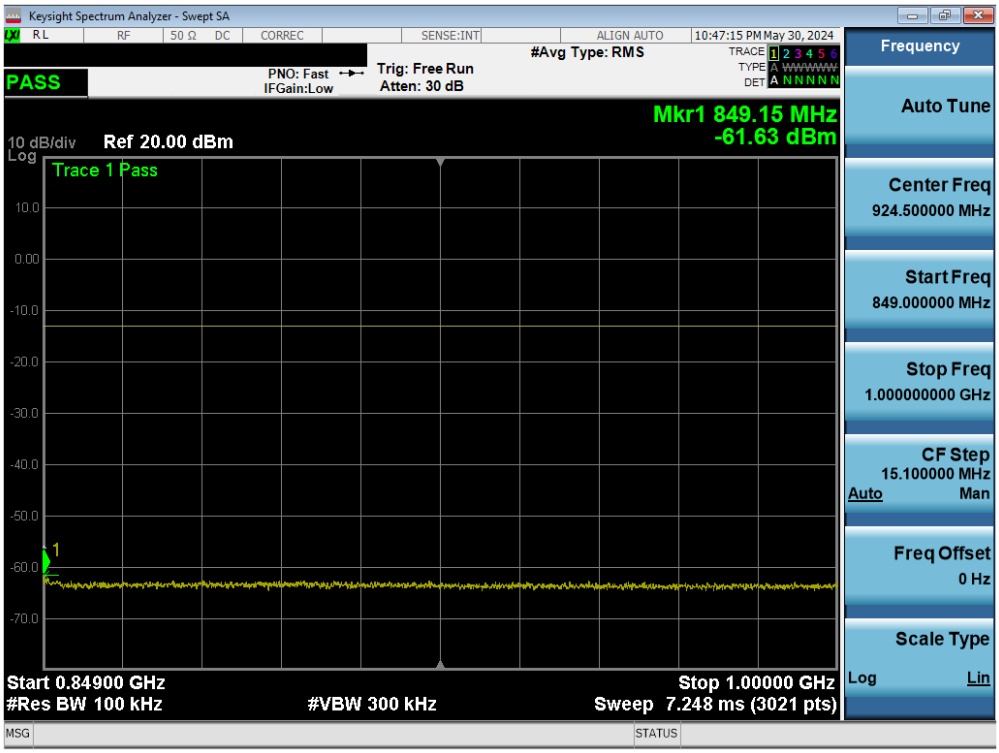
ULCA LTE Band 5



Plot 7-51. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz QPSK – PCC 1/49 SCC 1/0 - Low Channel)



Plot 7-52. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz QPSK – PCC 1/49 SCC 1/0 - Low Channel)

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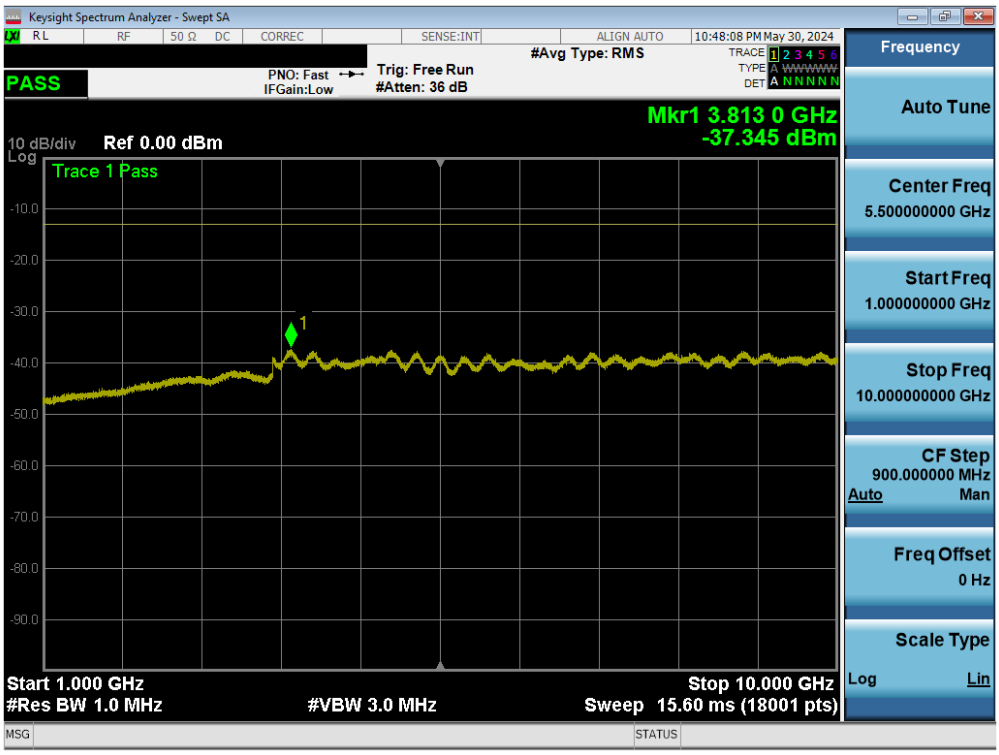
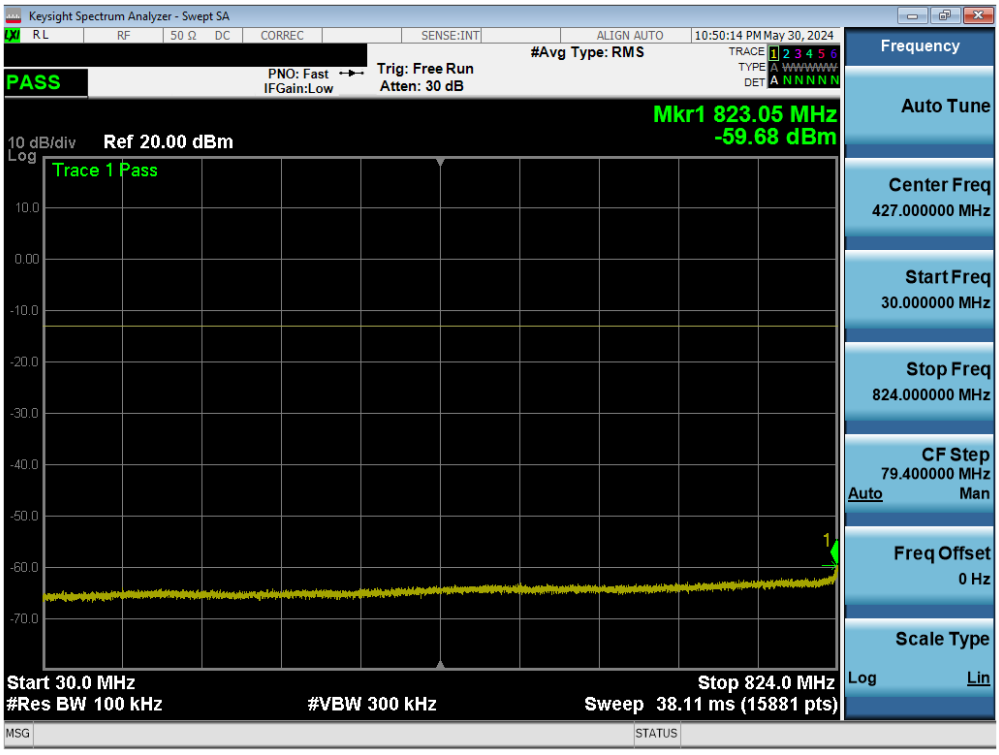


Plot 7-53. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz QPSK – PCC 1/49 SCC 1/0 - Low Channel)



Plot 7-54. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz QPSK – PCC 1/49 SCC 1/0 - Mid Channel)

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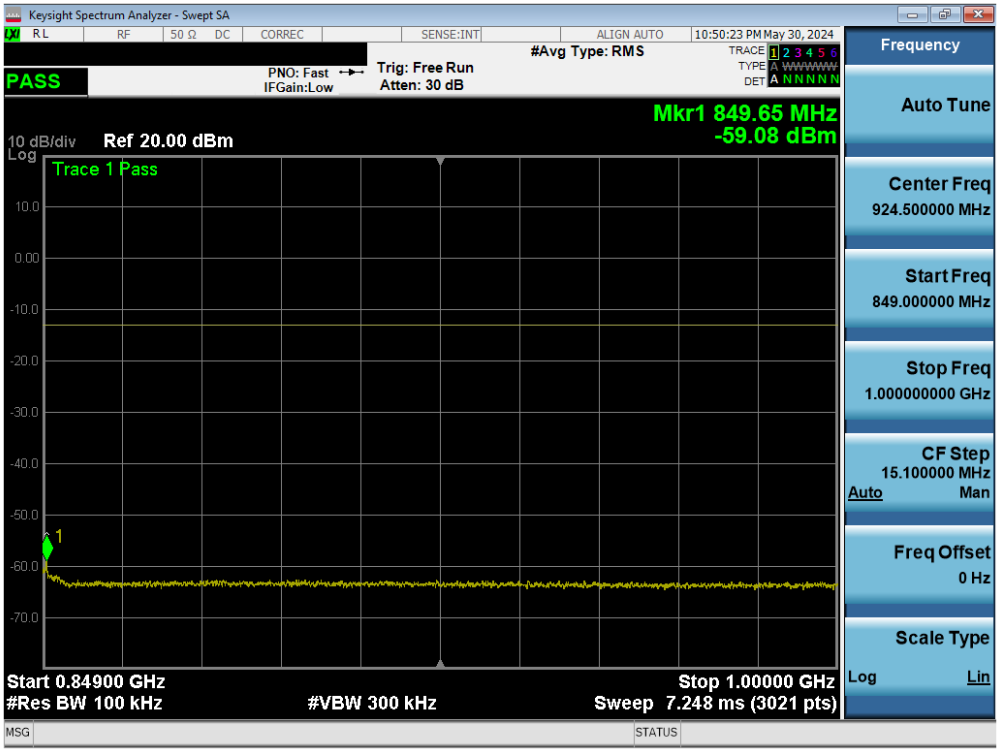
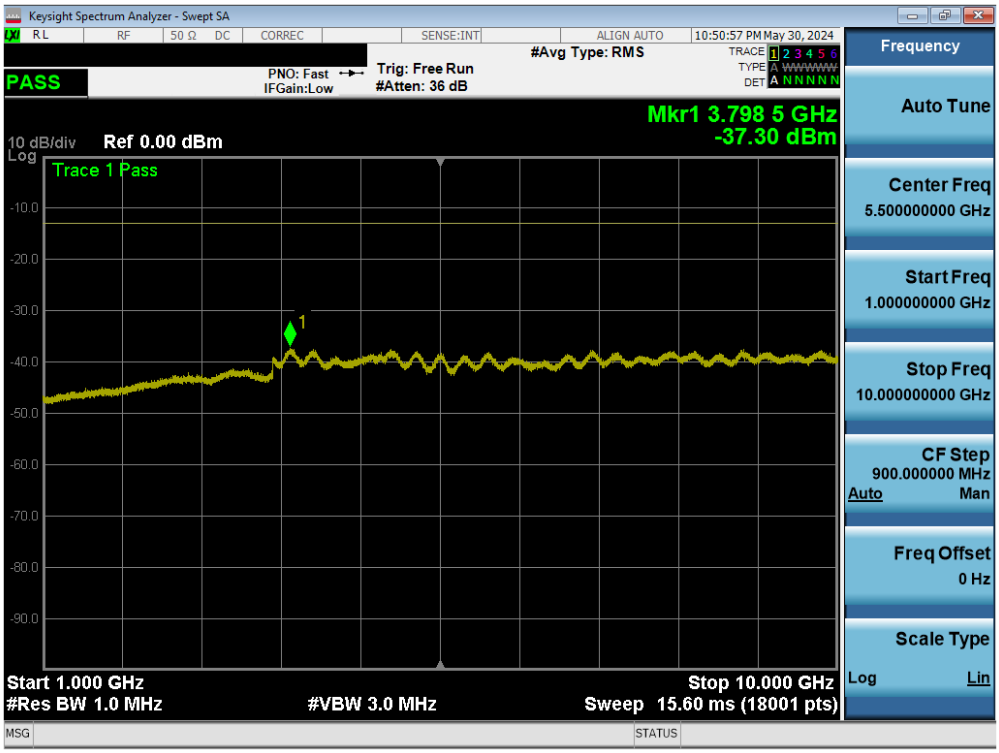


Plot 7-55. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz QPSK – PCC 1/49 SCC 1/0 - Mid Channel)



Plot 7-56. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz QPSK – PCC 1/49 SCC 1/0 - Mid Channel)

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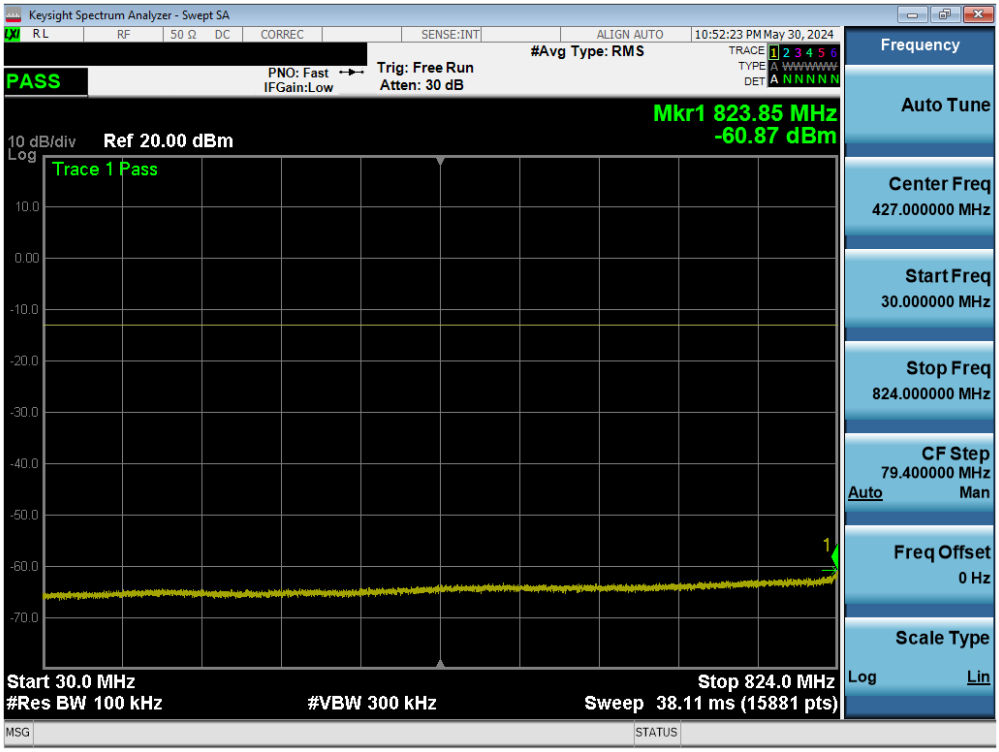
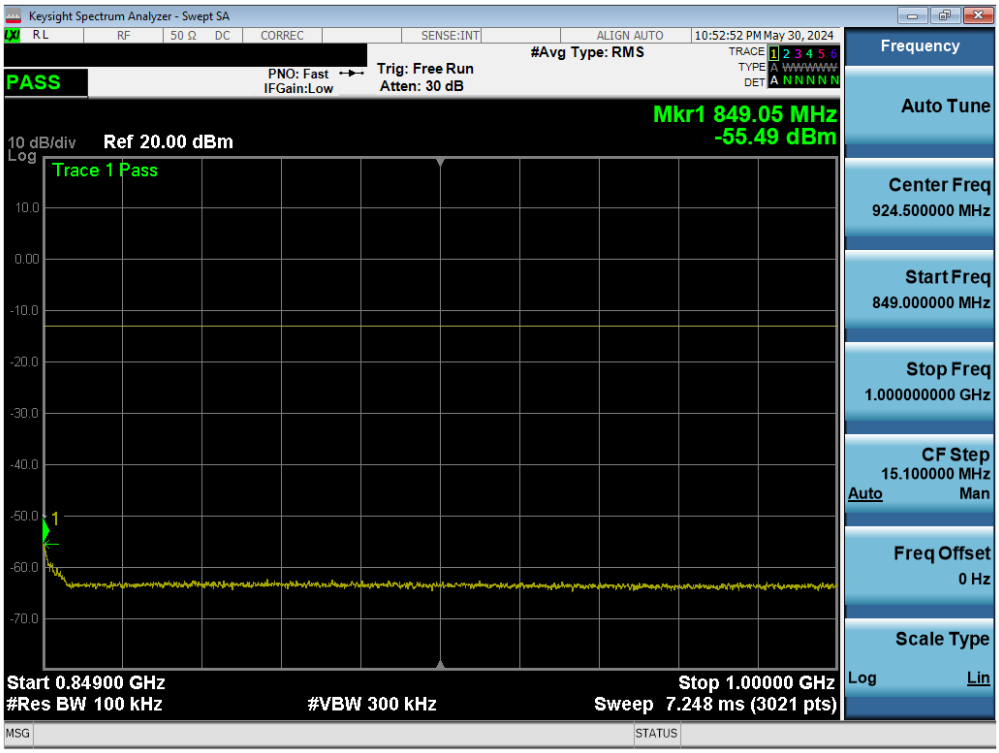


Plot 7-57. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz QPSK – PCC 1/0 SCC 1/49 - High Channel)



Plot 7-58. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz QPSK – PCC 1/0 SCC 1/49 - High Channel)

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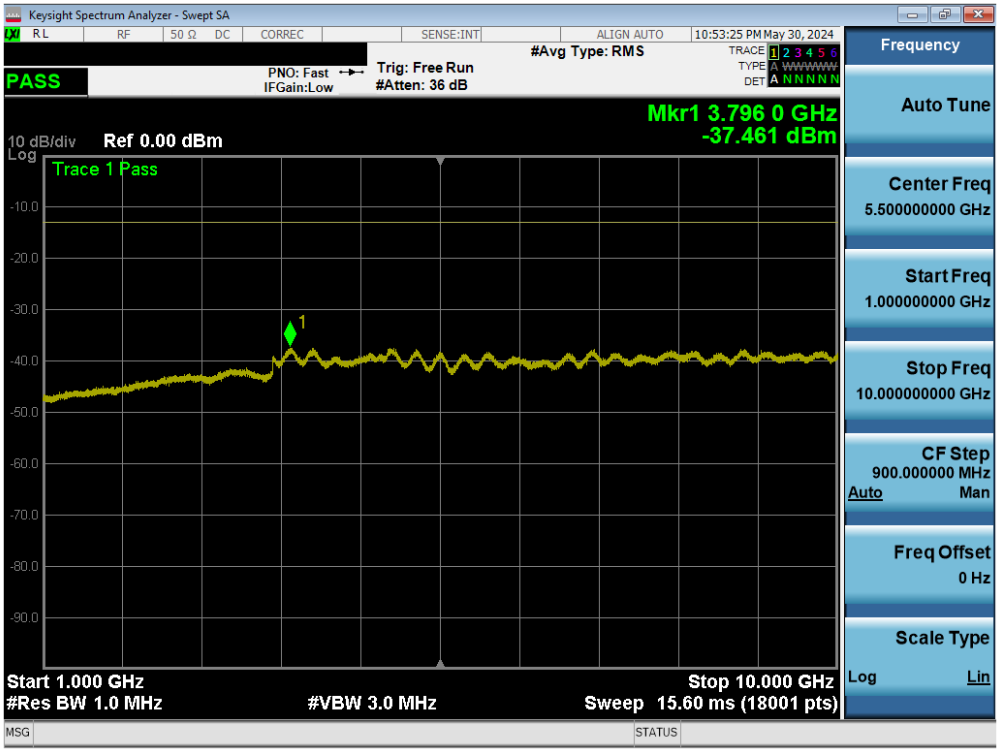

Plot 7-59. Conducted Spurious Plot (ULCA LTE Band 5 – (10 + 10)MHz QPSK – PCC 1/0 SCC 1/49 - High Channel)

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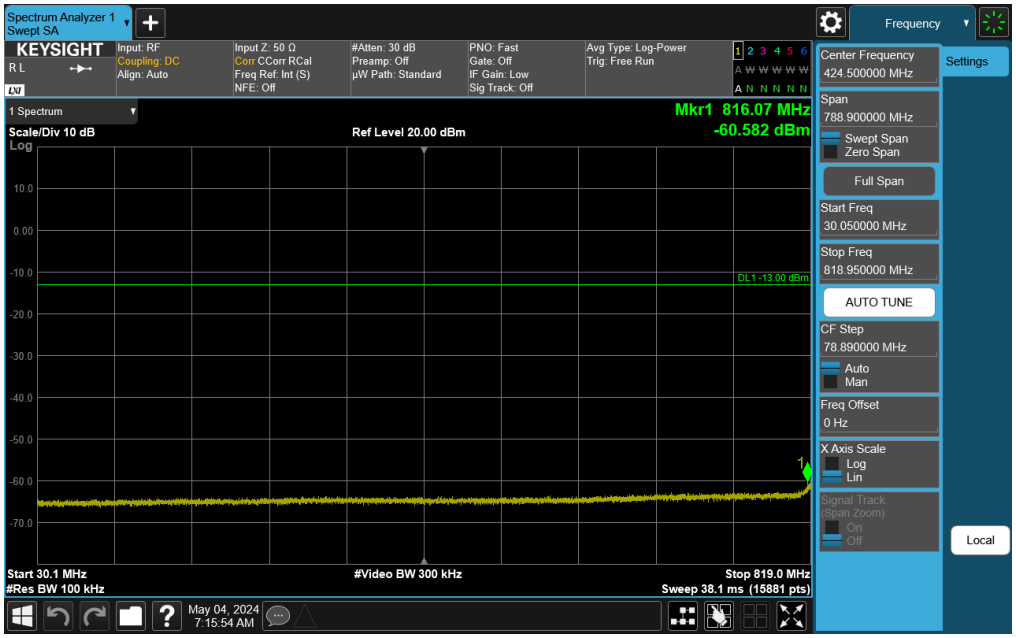
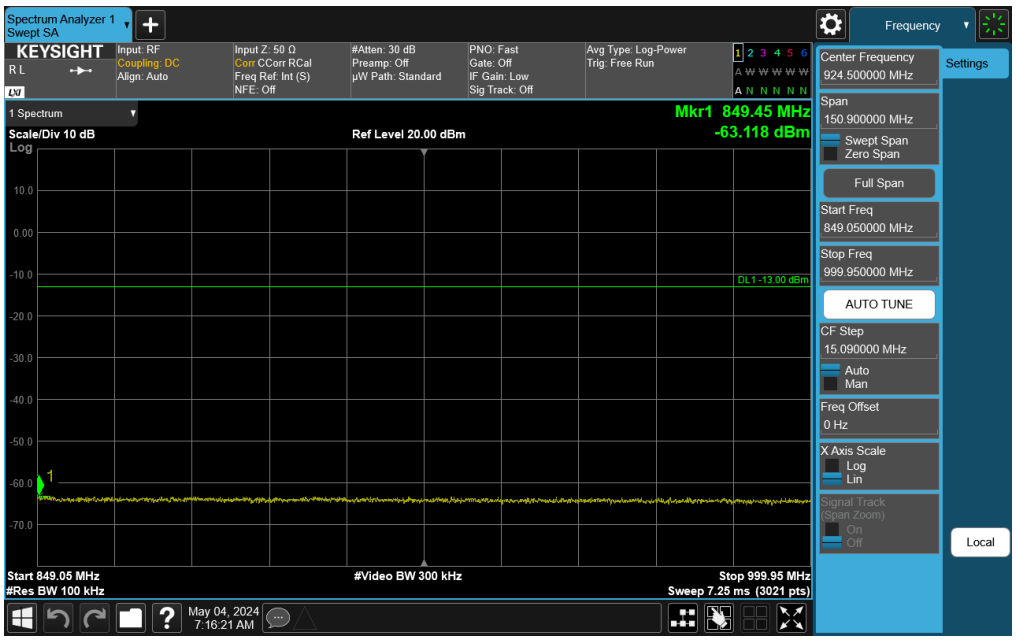
NR Band n26/n5



Plot 7-60. Conducted Spurious Plot (NR Band n26/n5 - 20.0MHz DFT-s-OFDM QPSK - RB Size 1, RB Offset 0 - Low Channel)



Plot 7-61. Conducted Spurious Plot (NR Band n26/n5 - 20.0MHz DFT-s-OFDM QPSK - RB Size 1, RB Offset 0 - Low Channel)

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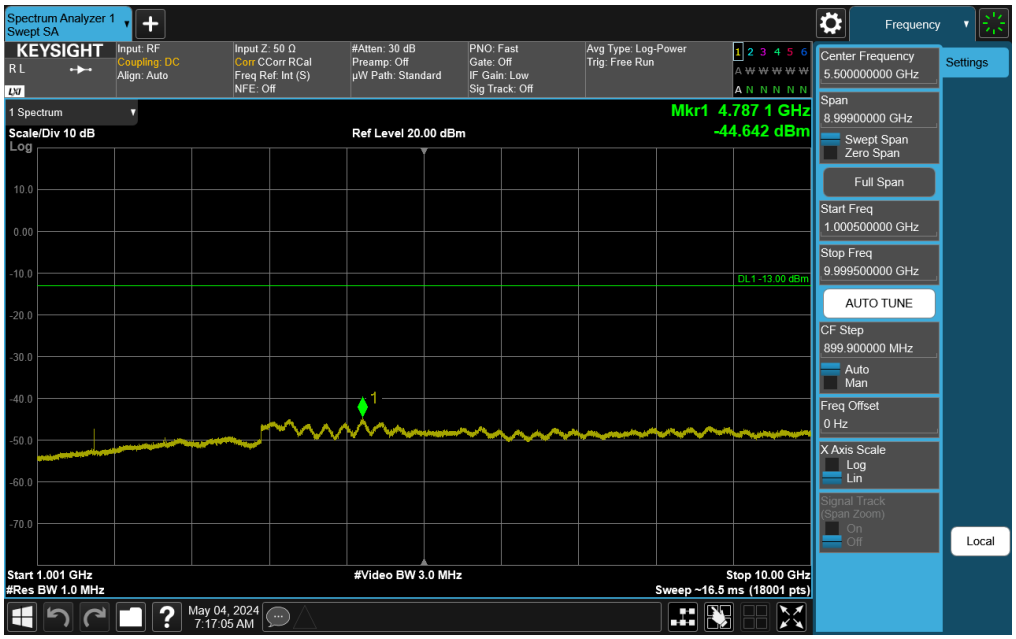
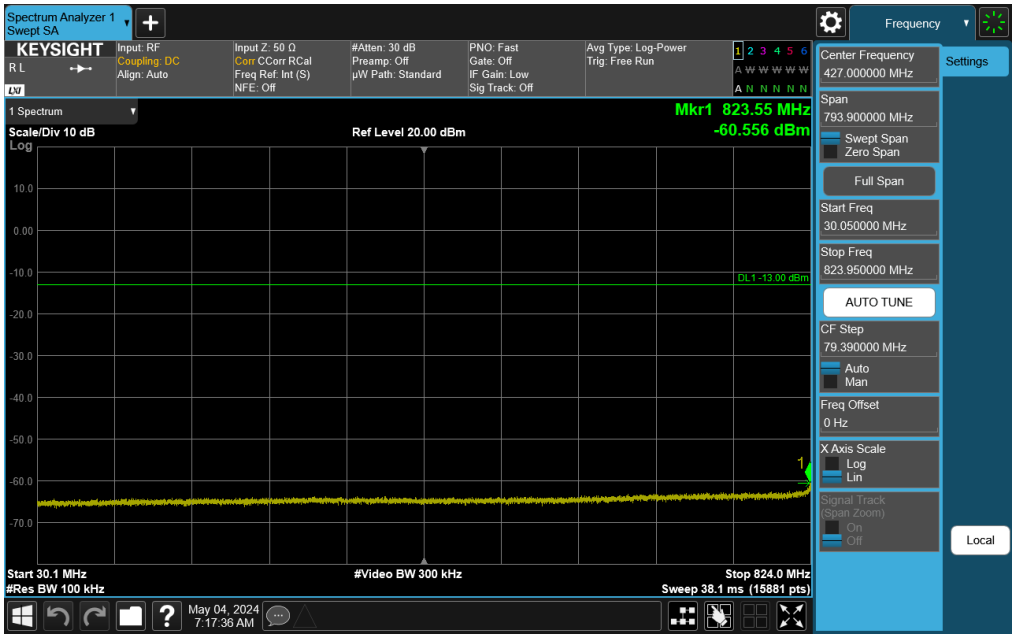


Plot 7-62. Conducted Spurious Plot (NR Band n26/n5 - 20.0MHz DFT-s-OFDM QPSK - RB Size 1, RB Offset 0 - Low Channel)



Plot 7-63. Conducted Spurious Plot (NR Band n26/n5 - 20.0MHz DFT-s-OFDM QPSK - RB Size 1, RB Offset 0 - Mid Channel)

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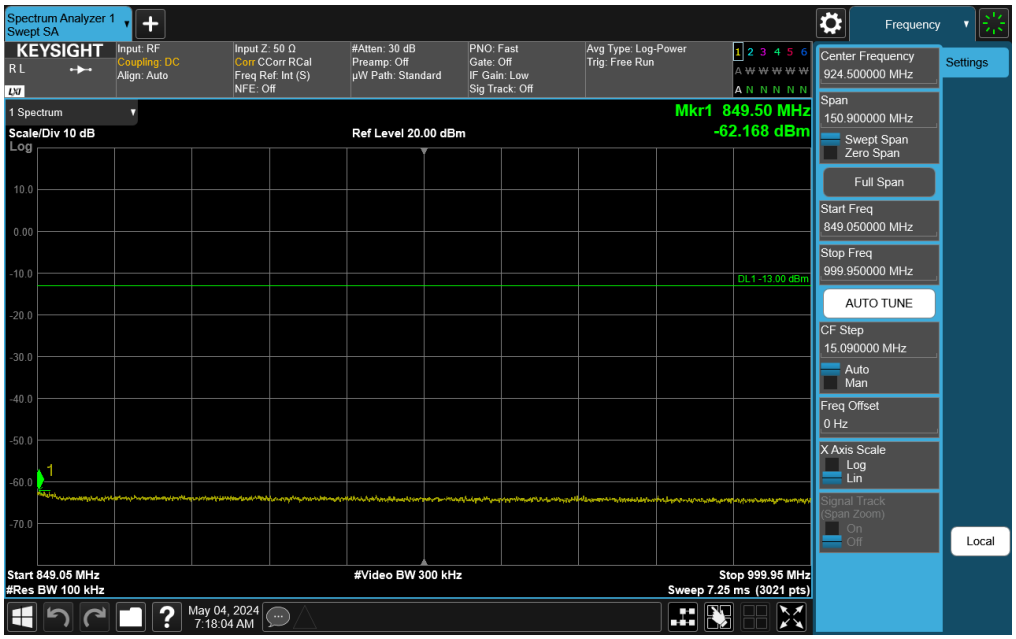
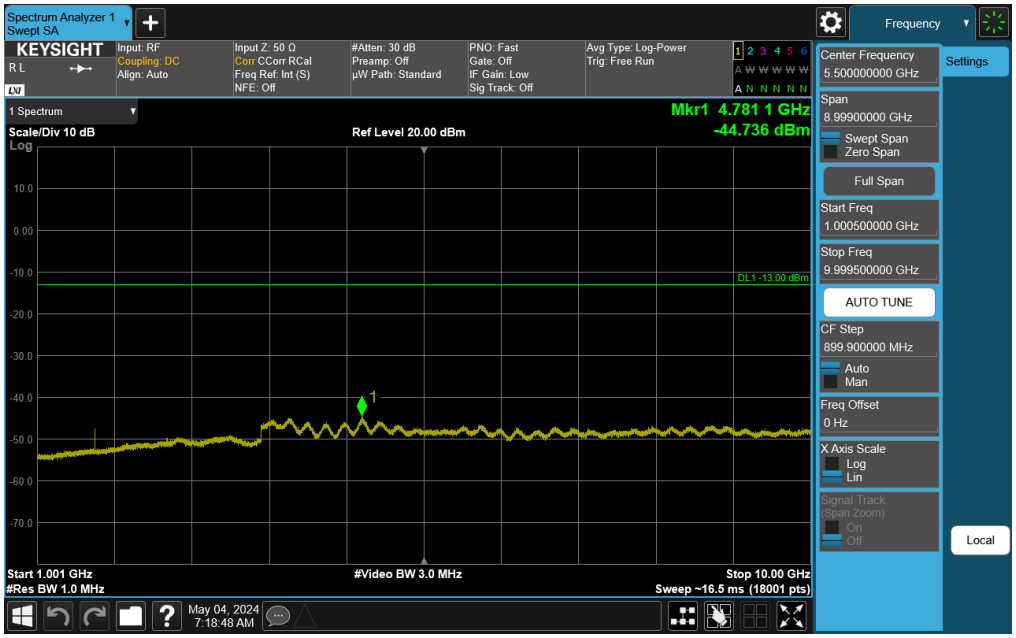


Plot 7-64. Conducted Spurious Plot (NR Band n26/n5 - 20.0MHz DFT-s-OFDM QPSK - RB Size 1, RB Offset 0 - Mid Channel)



Plot 7-65. Conducted Spurious Plot (NR Band n26/n5 - 20.0MHz DFT-s-OFDM QPSK - RB Size 1, RB Offset 0 - Mid Channel)

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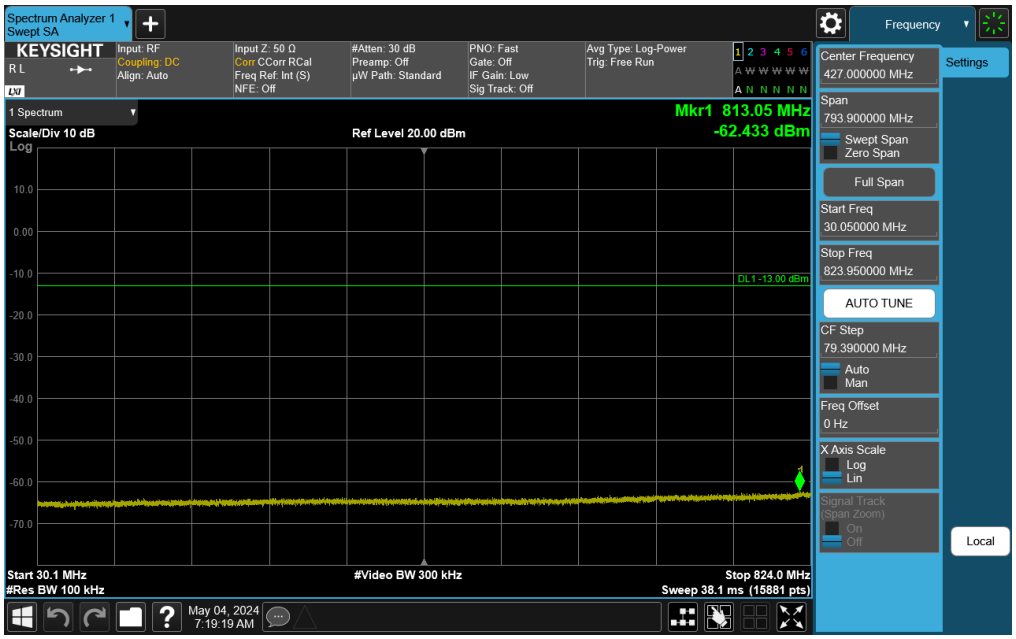
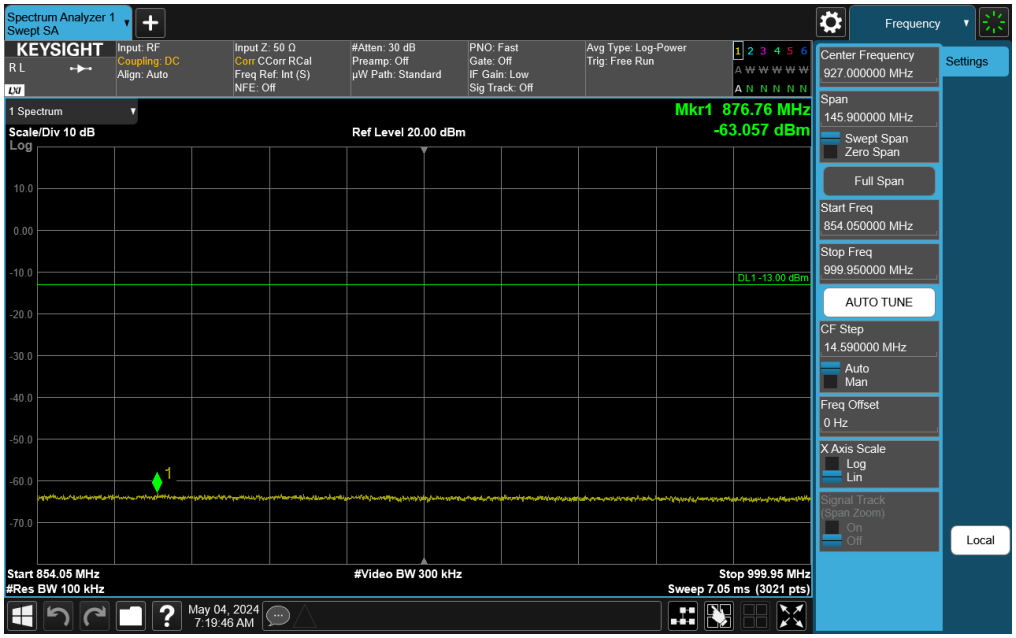


Plot 7-66. Conducted Spurious Plot (NR Band n26/n5 - 20.0MHz DFT-s-OFDM QPSK - RB Size 1, RB Offset 0 - High Channel)



Plot 7-67. Conducted Spurious Plot (NR Band n26/n5 - 20.0MHz DFT-s-OFDM QPSK - RB Size 1, RB Offset 0 - High Channel)

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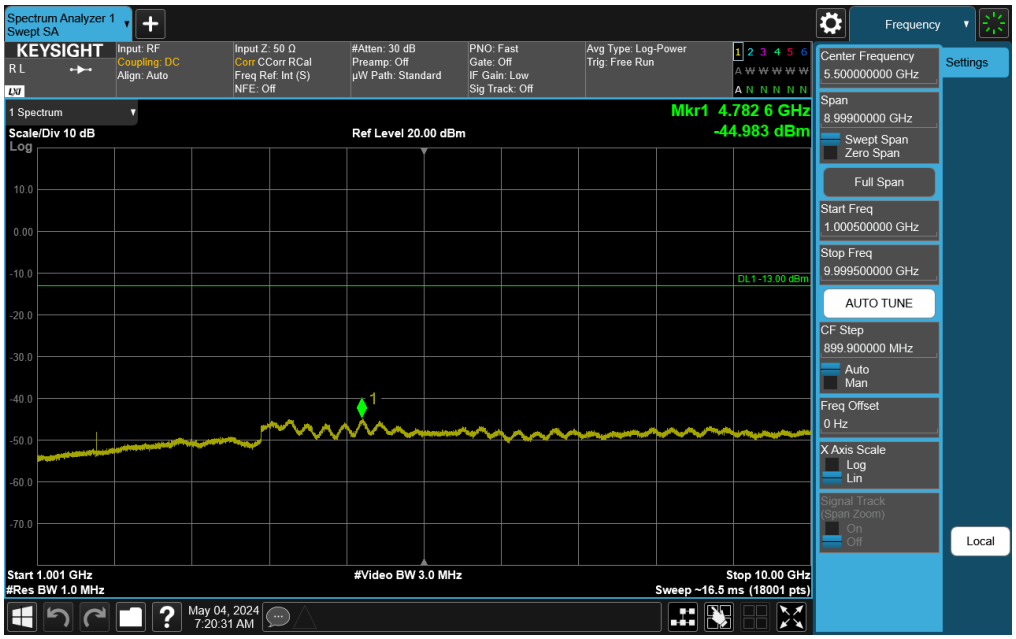

Plot 7-68. Conducted Spurious Plot (NR Band n26/n5 - 20.0MHz DFT-s-OFDM QPSK - RB Size 1, RB Offset 0 - High Channel)

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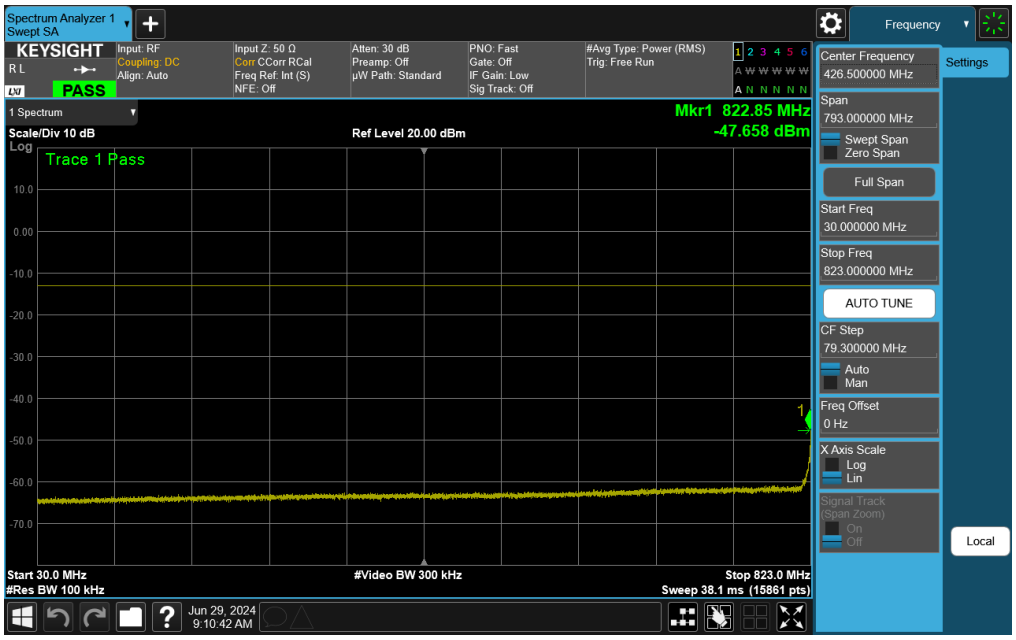
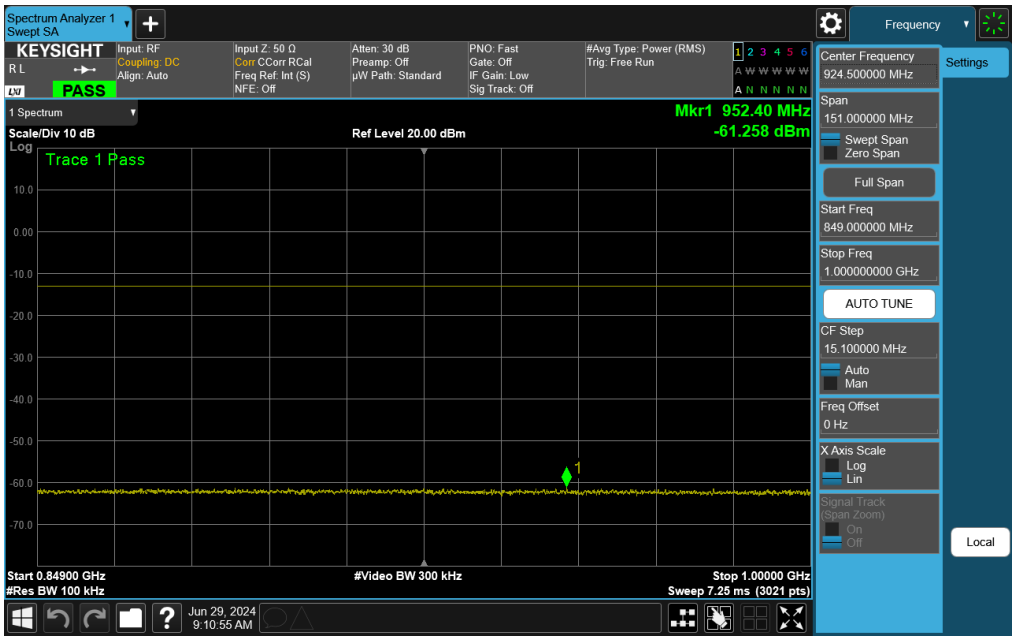
WCDMA Cell



Plot 7-69. Conducted Spurious Plot (WCDMA Ch. 4132)



Plot 7-70. Conducted Spurious Plot (WCDMA Ch. 4132)

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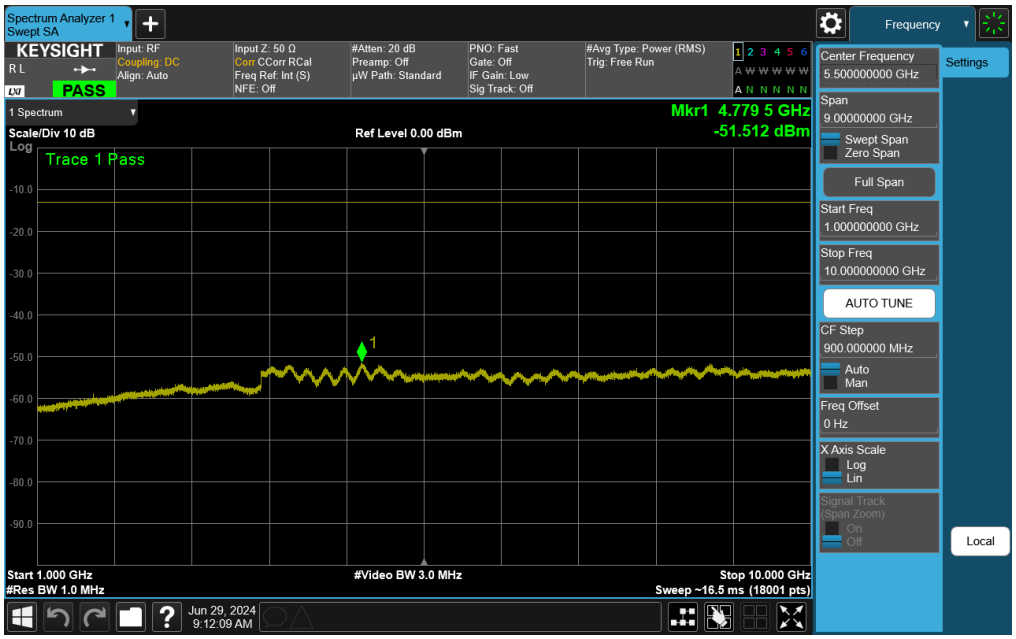
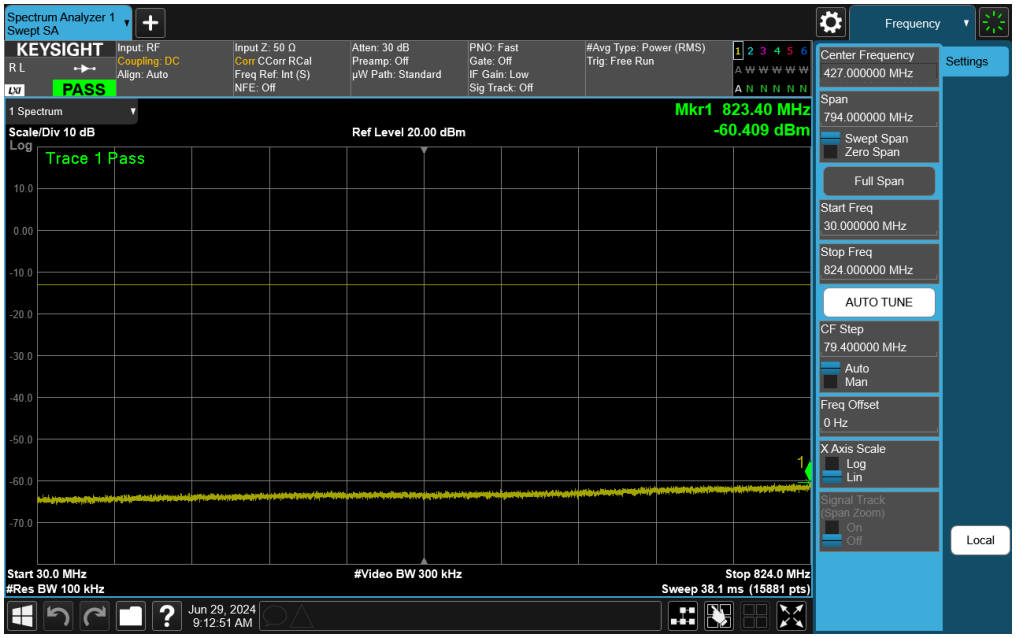


Plot 7-71. Conducted Spurious Plot (WCDMA Ch. 4132)



Plot 7-72. Conducted Spurious Plot (WCDMA Ch. 4183)

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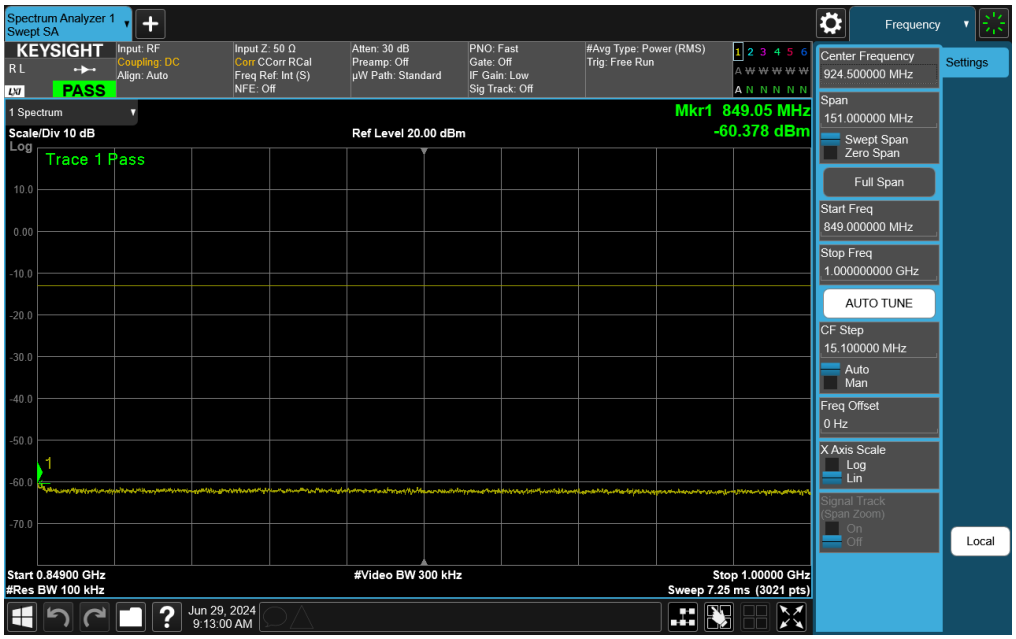
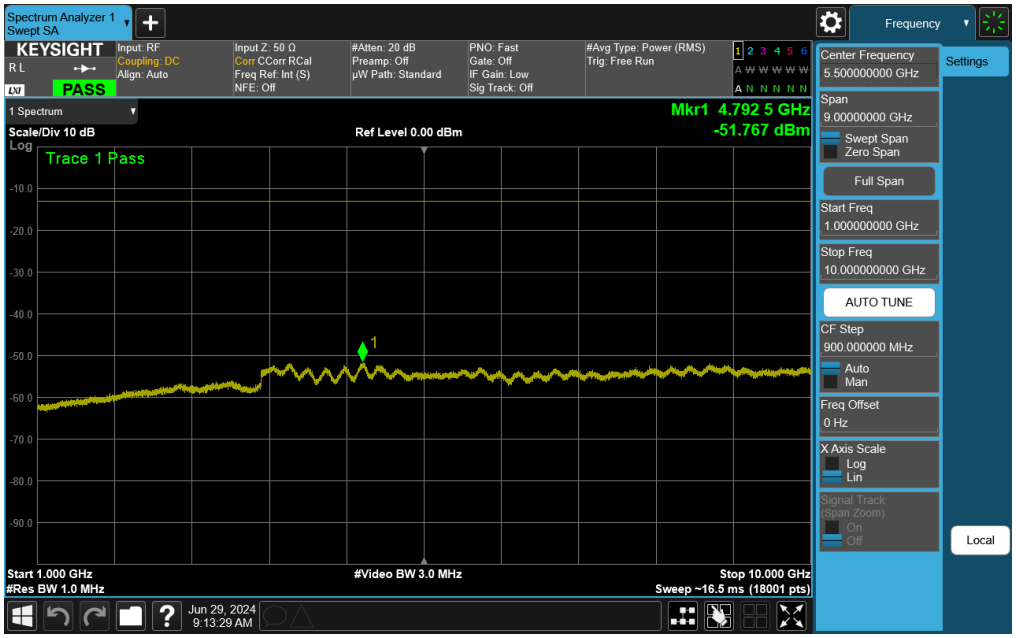


Plot 7-73. Conducted Spurious Plot (WCDMA Ch. 4183)



Plot 7-74. Conducted Spurious Plot (WCDMA Ch. 4183)

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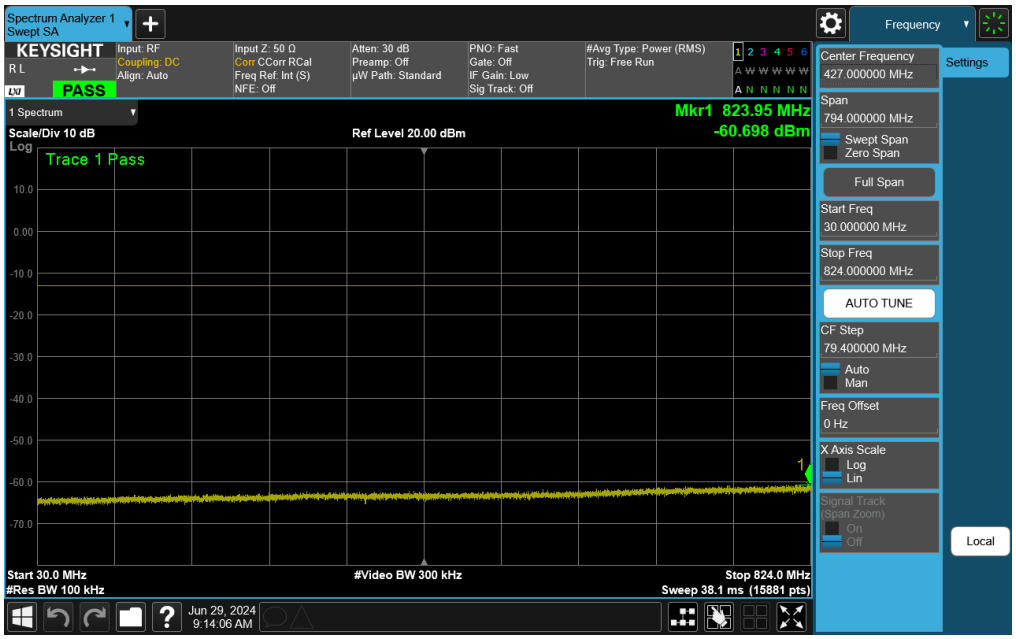
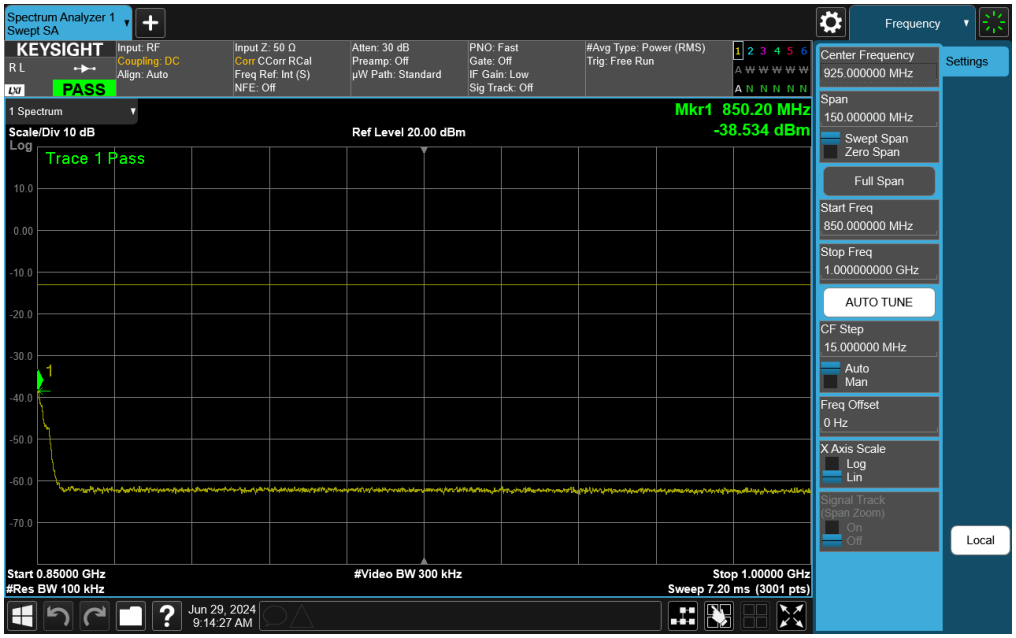


Plot 7-75. Conducted Spurious Plot (WCDMA Ch. 4233)



Plot 7-76. Conducted Spurious Plot (WCDMA Ch. 4233)

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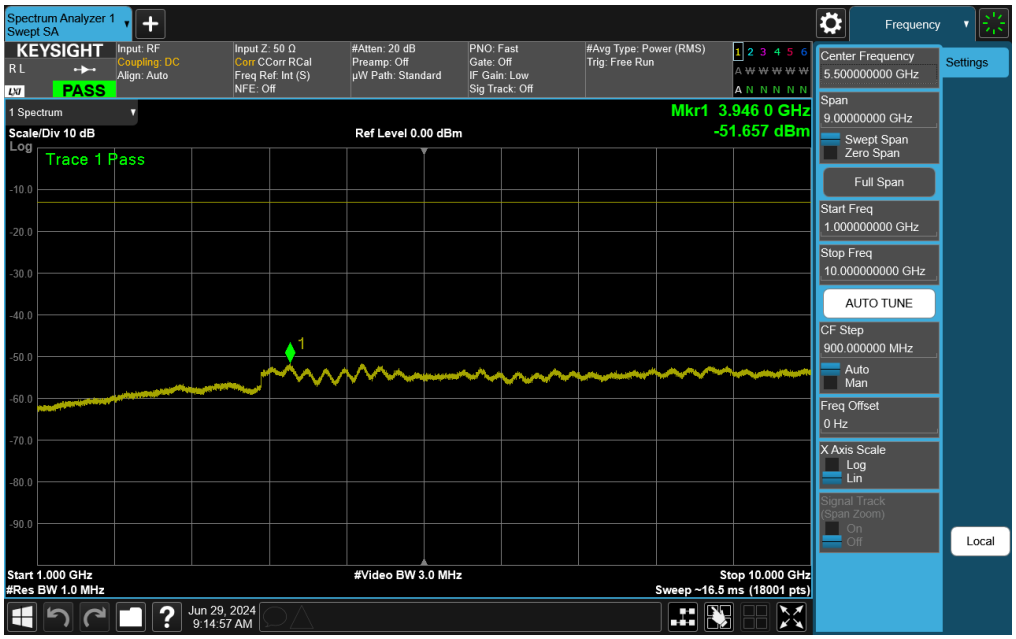

Plot 7-77. Conducted Spurious Plot (WCDMA Ch. 4233)

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7.4 Band Edge Emissions at Antenna Terminal

§2.1051, 22.917(a)

Test Overview and limit

All out of band emissions are measured with a spectrum analyzer connected to the antenna terminal of the EUT while the EUT is operating at maximum power, and at the appropriate frequencies. All data rates were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section. All ports were tested and only the worst case data was reported.

The minimum permissible attenuation level of any spurious emission is 43 + 10 $\log_{10}(P_{[Watts]})$, where P is the transmitter power in Watts.

Test Procedure Used

KDB 971168 D01 v03r01 – Section 6.0

Test Settings

1. Start and stop frequency were set such that the band edge would be placed in the center of the plot
2. Span was set large enough so as to capture all out of band emissions near the band edge
3. RBW ≥ 1% of the emission bandwidth
4. VBW ≥ 3 x RBW
5. Detector = RMS
6. Number of sweep points ≥ 2 x Span/RBW
7. Trace mode = trace average for continuous emissions, max hold for pulse emissions
8. Sweep time = auto couple
9. The trace was allowed to stabilize

Test Setup

The EUT and measurement equipment were set up as shown in the diagram below.

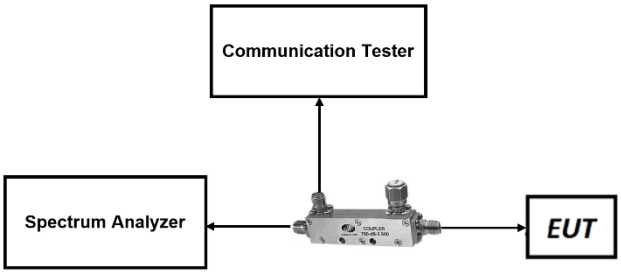

Figure 7-5. LTE Test Instrument & Measurement Setup

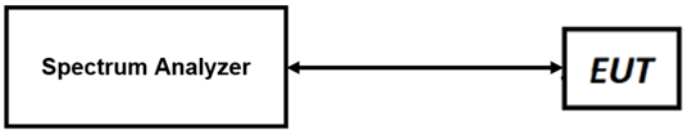

Figure 7-6. FR1 Test Instrument & Measurement Setup

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Test Notes

1. Per 22.917(b), in the 1 MHz bands immediately outside and adjacent to the frequency block a resolution bandwidth of at least one percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to demonstrate compliance with the out-of-band emissions limit. The emission bandwidth is defined as the width of the signal between two points, one below the carrier center frequency and one above the carrier center frequency, outside of which all emission are attenuated at least 26 dB below the transmitter power.

2. For NR operation, all subcarrier spacings (SCS) and transmission schemes (e.g. CP-OFDM and DFT-s-OFDM) were investigated to determine the worst case configuration. All modes of operation were investigated and the worst case configuration results are reported in this section.

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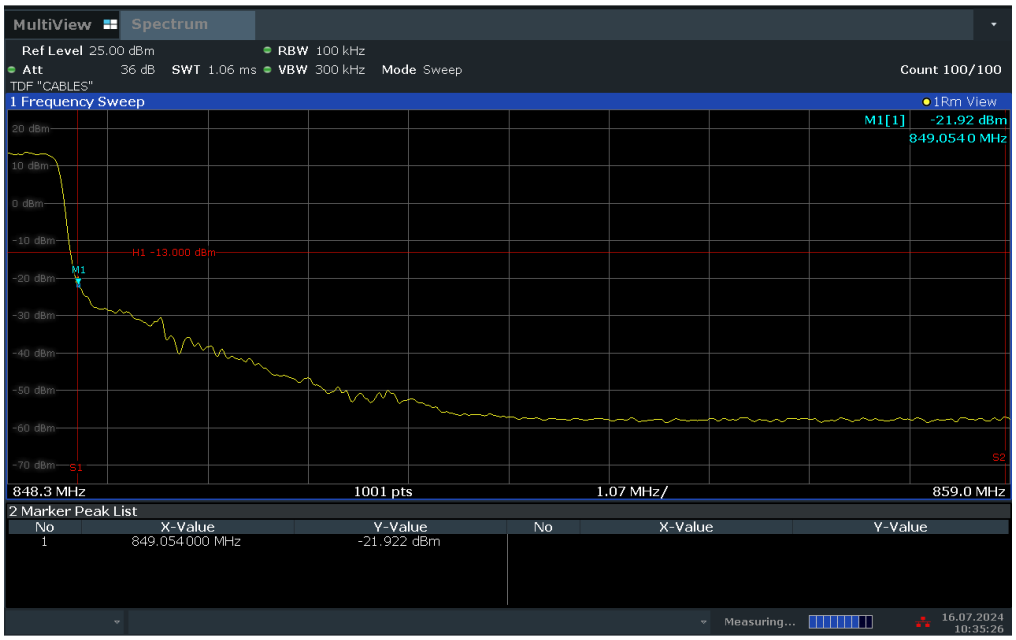
LTE Band 26

ACLRResults

10:33:58 16.07.2024

Plot 7-78. Lower BE Plot (LTE Band 26 – 1.4MHz QPSK – Full RB Configuration)

ACLRResults



10:35:27 16.07.2024

Plot 7-79. Upper BE Plot (LTE Band 26 – 1.4MHz QPSK – Full RB Configuration)

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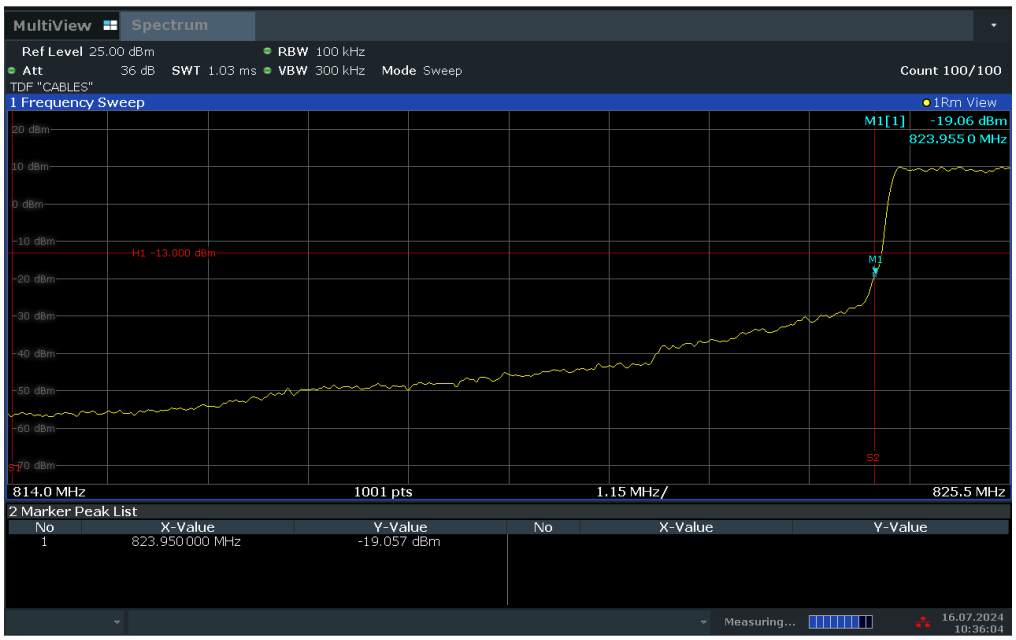
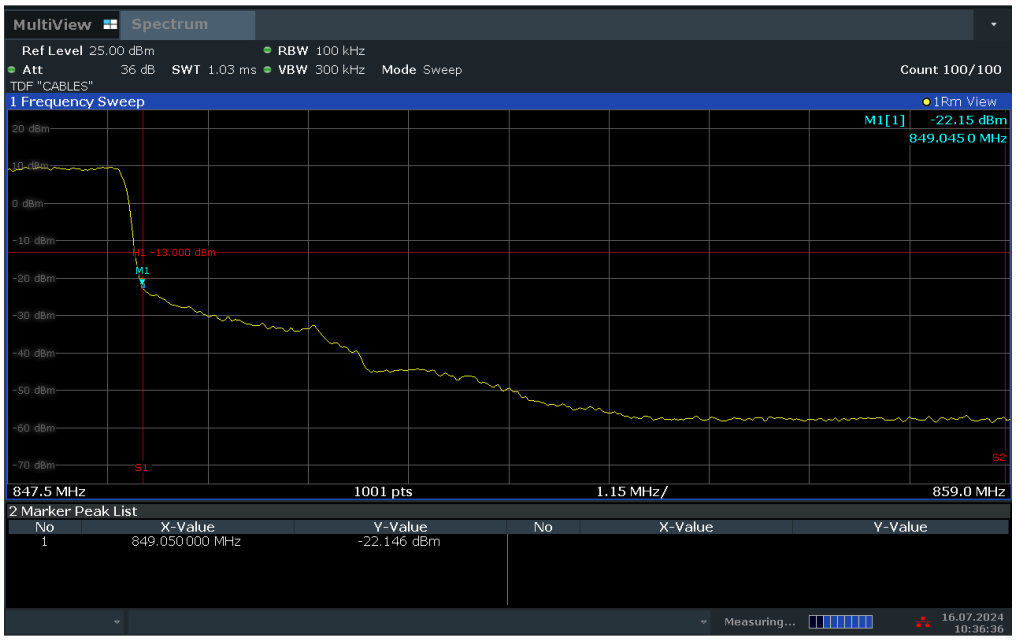
ACLRResults



10:36:05 16.07.2024

Plot 7-80. Lower BE Plot (LTE Band 26 - 3MHz QPSK – Full RB Configuration)

ACLRResults



10:36:37 16.07.2024

Plot 7-81. Upper BE Plot (LTE Band 26 - 3MHz QPSK – Full RB Configuration)

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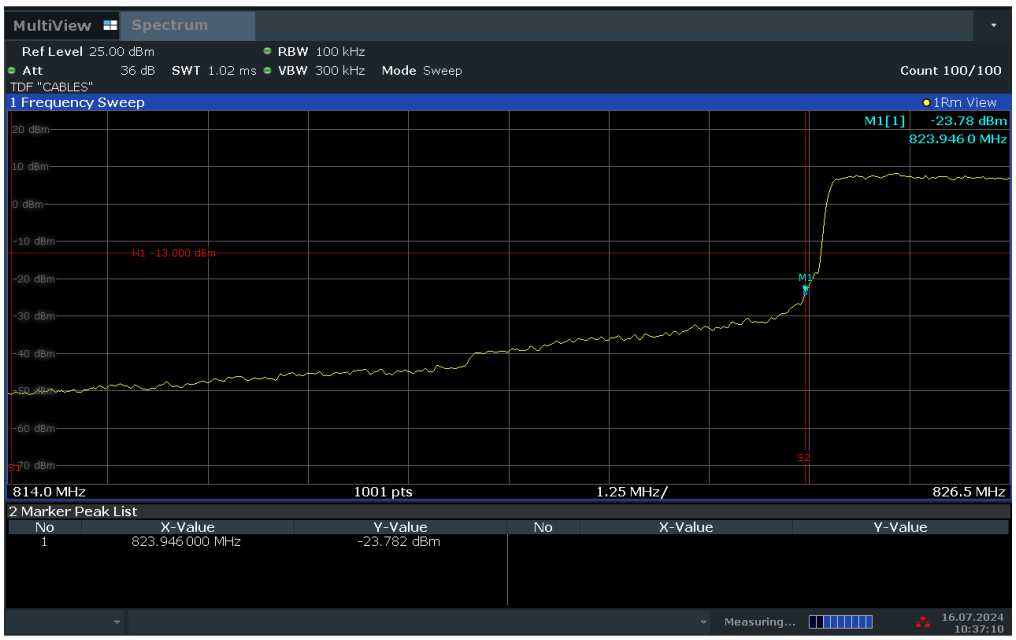
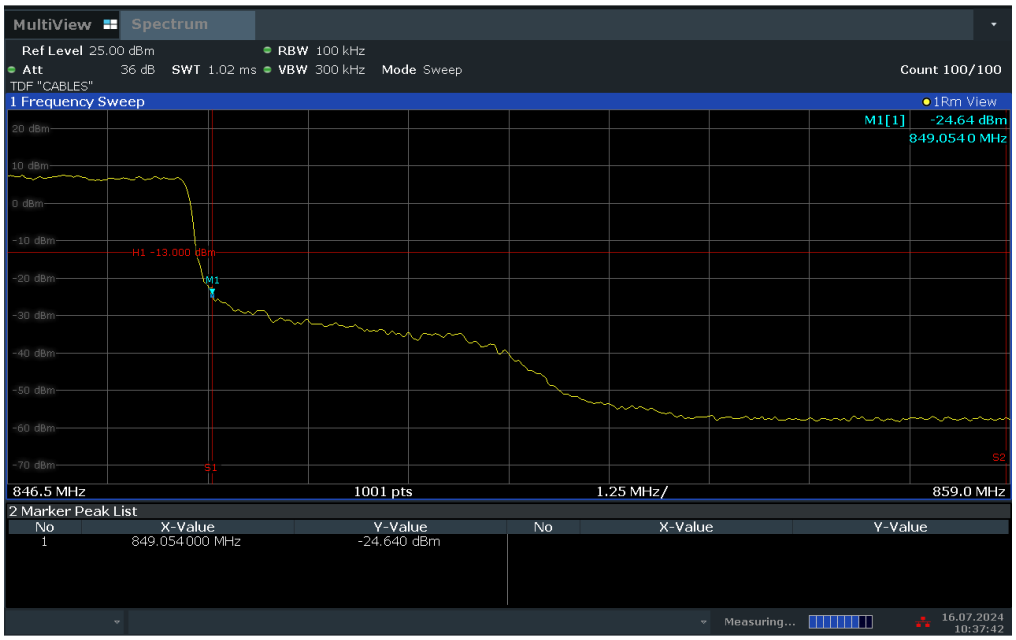
ACLRResults



10:37:10 16.07.2024

Plot 7-82. Lower BE Plot (LTE Band 26 - 5MHz QPSK – Full RB Configuration)

ACLRResults



10:37:43 16.07.2024

Plot 7-83. Upper BE Plot (LTE Band 26 - 5MHz QPSK – Full RB Configuration)

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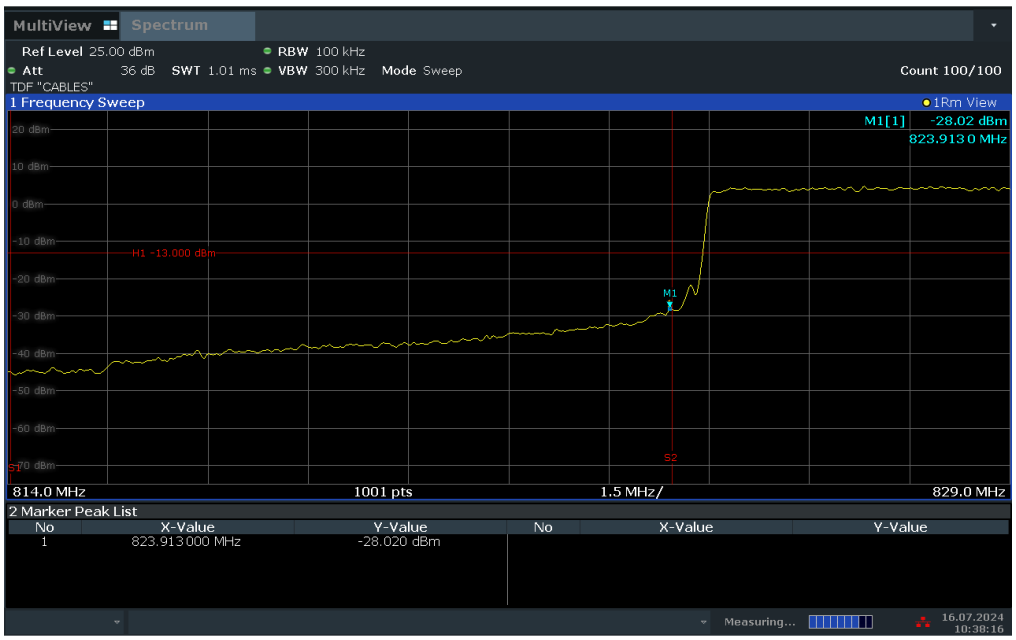
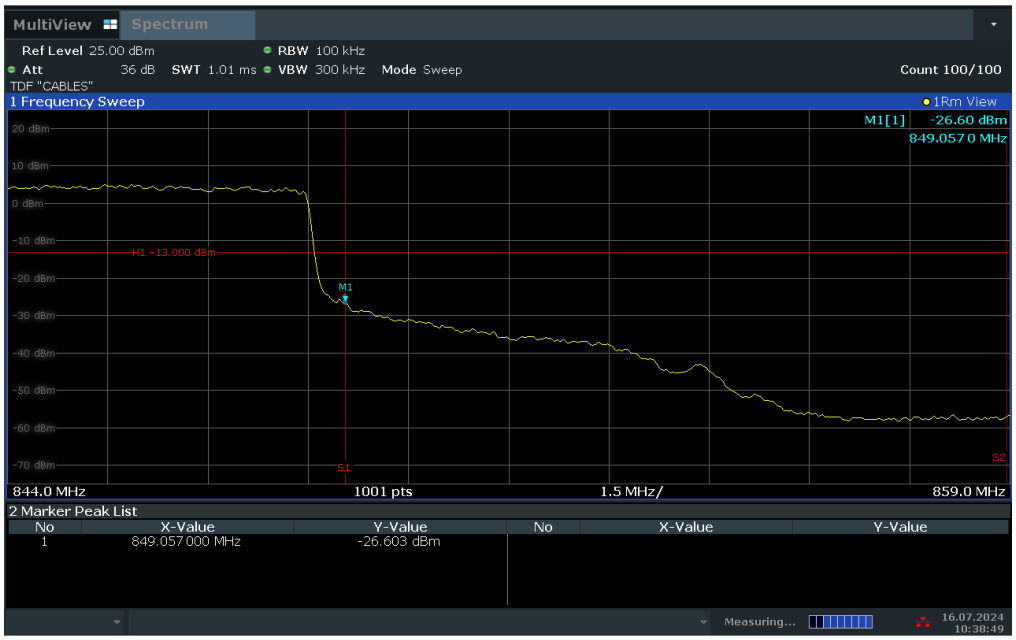
ACLRResults



10:38:17 16.07.2024

Plot 7-84. Lower BE Plot (LTE Band 26 - 10MHz QPSK – Full RB Configuration)

ACLRResults



10:38:49 16.07.2024

Plot 7-85. Upper BE Plot (LTE Band 26 - 10MHz QPSK – Full RB Configuration)

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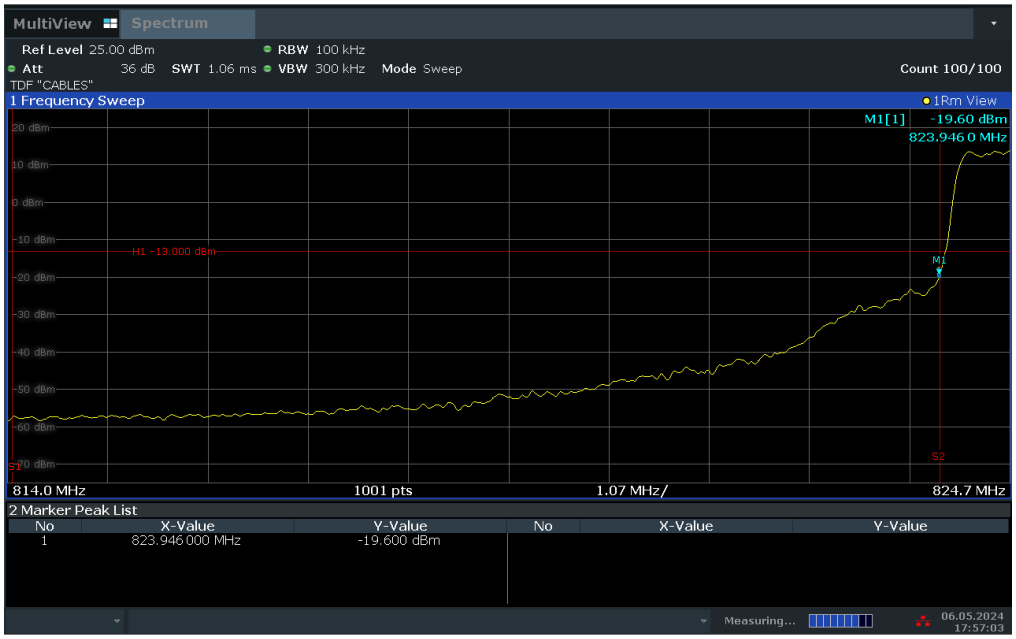
LTE Band 5

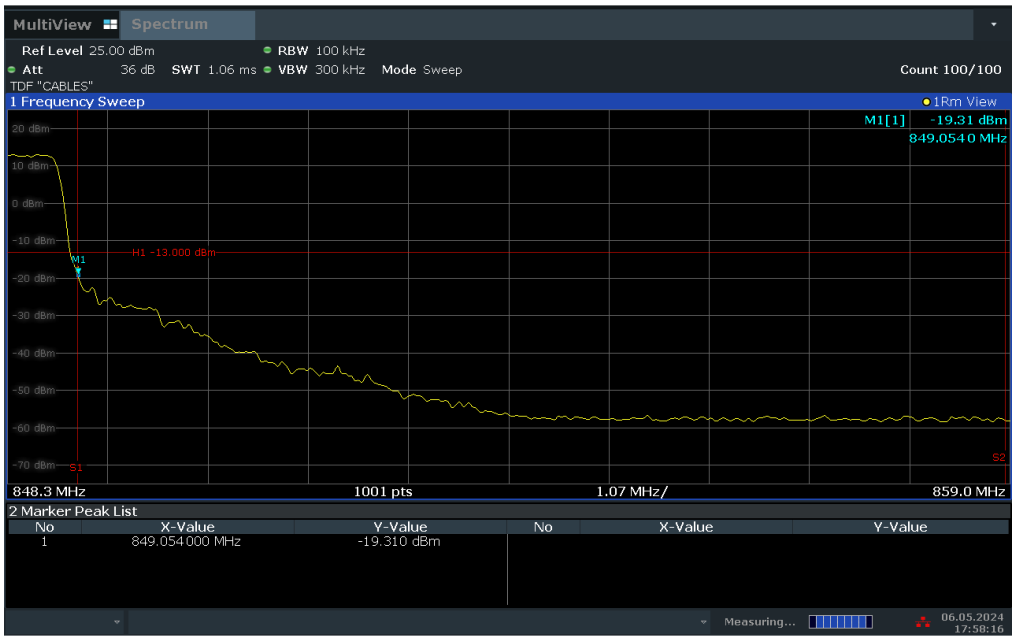
Peak



17:57:03 06.05.2024

Plot 7-86. Lower BE Plot (LTE Band 5 – 1.4MHz QPSK – Full RB Configuration)

Peak



17:58:17 06.05.2024

Plot 7-87. Upper BE Plot (LTE Band 5 – 1.4MHz QPSK – Full RB Configuration)

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